

SN54SC3T97-SEP Total Ionizing Dose (TID) Report



ABSTRACT

This report covers the Radiation Lot Acceptance Testing (RLAT) results of the SN54SC3T97-SEP radiation tolerant, multiple-function gate. The study was done to determine Total Ionizing Dose (TID) effects under high dose rate (HDR) to 30 krad(Si). Radiation Lot Acceptance Testing (RLAT) was performed using five units at a dose level of 30 krad(Si) per MIL-STD-883 TM 1019, and all future wafer lots will be tested to the same conditions.

The SN54SC3T97-SEP is packaged in a space enhanced plastic for low outgassing characteristics and is Single Event Latch-Up (SEL) immune up to 43 MeV-cm²/mg, which makes the device an option for low Earth orbit space applications.

For full total ionizing dose characterization results, see [SN54SC4T125-SEP Total Ionizing Dose \(TID\) Report](#).

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1 Device Information

The SN54SC3T97-SEP features configurable multiple functions with extended voltage operation to allow for voltage translation. The output state is determined by eight patterns of 3-bit inputs. The user can choose the logic functions of MUX, AND, OR, NAND, NOR, inverter, and non-inverter.

The output level is referenced to the supply voltage (V_{CC}) and supports 1.2-V, 1.8-V, 2.5-V, 3.3-V, and 5-V CMOS levels. The input is designed with a lower threshold circuit to support up translation for lower voltage CMOS inputs (for example, 1.2-V input to 1.8-V output or 1.8-V input to 3.3-V output.) Additionally, the 5-V tolerant input pins enable down translation (for example, 3.3-V to 2.5-V output).

1.1 Device Details

Table 1-1 lists the device information used for TID HDR Radiation Lot Acceptance Testing (RLAT).

Table 1-1. Device and Exposure Details

TID HDR Details: up to 30 krad(Si)	
TI Device Number	SN54SC3T97-SEP
Package	14-pin PW (TSSOP)
Technology	LBC9
Die Lot Number	3059497RFB
A/T Lot Number and Date Code	3632644ML3 / 36AEQPK
Quantity Tested	12 irradiated devices + 4 control
Lot Accept or Reject	Devices passed 30 krad(Si)
HDR Radiation Facility	Texas Instruments CLAB in Dallas, Texas
HDR Dose Level	30 krad(Si)
HDR Dose Rate	196.01 -rad(Si)/s ionizing radiation
HDR Radiation Source	Gammacell 220 Excel (GC-220E) Co-60
Irradiation Temperature	Ambient, room temperature

2 Total Dose Test Setup

2.1 Test Overview

The SN54SC3T97-SEP samples were irradiated at a high dose rate of 196.01 rad(Si)/s up to 30 krad(Si) and then put through full electrical parametric testing on the production Automated Test Equipment (ATE). The samples were functional and passed all electrical parametric tests with readings within data sheet electrical specification limits.

2.2 Test Description and Facilities

The SN54SC3T97-SEP HDR exposure was performed on biased devices in a Co-60 gamma cell at TI facility in Dallas, Texas. The un-attenuated dose rate of this cell is 196.01 rads(Si)/s. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and full post radiation electrical evaluation using Texas Instruments ATE was conducted. ATE test limits are set per data sheet electrical limits based on qualification and characterization data. Post radiation measurements were taken within 30 minutes of removing the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post radiation measurements.

2.3 Test Setup Details

The devices were tested in biased conditions as described in the following sections.

2.3.1 Bias Diagram

Figure 2-1 shows the bias conditions for each pin during irradiation.

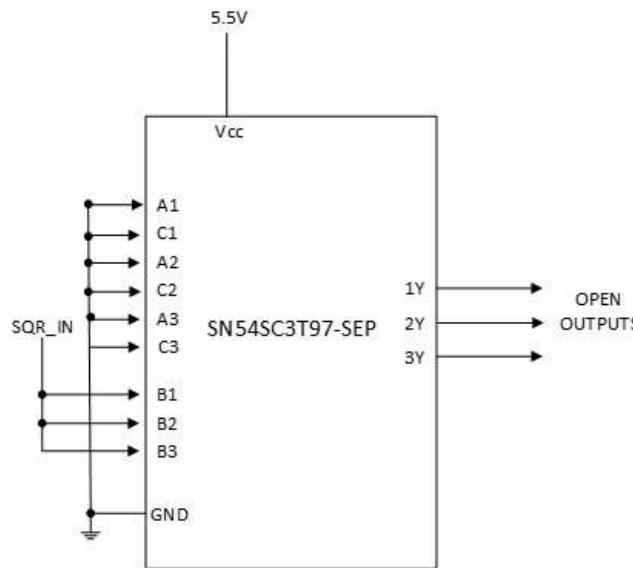


Figure 2-1. SN54SC3T97-SEP Biased Diagram

2.4 Test Configuration and Condition

The RLAT units were irradiated to 30 krad(Si), parametrically tested on ATE, and then were annealed at 25°C for 50 hours. The units were then put through parametric testing once more on the ATE. An additional six units were irradiated to 30 krad(Si) without anneal, for reference.

Table 2-1 lists the serialized samples used for TID Radiation Lot Acceptance Testing (RLAT).

Table 2-1. HDR Device Information

Control Group	HDR = 196.01 rad(Si)/s	
Total Samples: 3	Total Samples: 12	
Exposure Levels		
0 krad (Si)	30 krad(Si)	
Biased	Biased	Biased + 50 hour anneal
1 - 4	5 - 10	11 - 16

3 TID Characterization Test Results

3.1 TID Characterization Summary Results

The parametric data for the SN54SC3T97-SEP passes to 30 krad(Si) HDR TID irradiation. The drifts of the electrical parameters through HDR were within the data sheet limits.

Overall, the SN54SC3T97-SEP showed a strong degree of hardness to HDR TID irradiation up to 30 krad(Si). The measurements taken post-irradiation for each sample set showed a marginal shift for most parameters at each dose level. The parameters that did show a greater degree of change between pre- and post-irradiation were still within the electrical performance characteristics specified in the data sheet electrical parameters.

See [Section 5](#) for HDR report to 30 krad(Si).

3.2 Specification Compliance Matrix

Table 3-1. Electrical Parameters Table

Parameter	Test Conditions	V _{CC}	T _A = -55°C to +125°C			Unit	Test Name
			MIN	TYP	MAX		
V _{T+} 1	Positive-going input threshold voltage	1.2 V to 1.3 V	0.31	0.655	1.1	V	VTP_1P2V
		1.65 V to 2 V	0.39	0.915	1.32		VTP_1P65V, VTP_2V
		2.25 V to 2.75 V	0.51	1.09	1.51		VTP_2P25V, VTP_2P75V
		3 V to 3.6 V	0.65	1.2	1.7		VTP_3V, VTP_3P6V
		4.5 V to 5.5 V	0.87	1.51	2.16		VTP_4P5V, VTP_5P5V
V _{T-} 1	Negative-going input threshold voltage	1.2 V to 1.3 V	0.11	0.349	0.622	V	VTN_1P2V
		1.65 V to 2 V	0.18	0.455	0.666		VTN_1P65V, VTN_2V
		2.25 V to 2.75 V	0.25	0.545	0.74		VTN_2P25V, VTN_2P75V
		3 V to 3.6 V	0.33	0.635	0.85		VTN_3V, VTN_3P6V
		4.5 V to 5.5 V	0.45	0.755	1.14		VTN_4P5V, VTN_5P5V
ΔV _T 1	Hysteresis (V _{T+} – V _{T-})	1.2 V to 1.3 V	0.081	0.29	0.77	V	DELTAVT_1P2V
		1.65 V to 2 V	0.21	0.43	0.88		DELTAVT_1P65V, DELTAVT_2V
		2.25 V to 2.75 V	0.25	0.54	0.91		DELTAVT_2P25V, DELTAVT_2P75V
		3 V to 3.6 V	0.31	0.63	0.91		DELTAVT_3V, DELTAVT_3P6V
		4.5 V to 5.5 V	0.43	0.75	1.1		DELTAVT_4P5V, DELTAVT_5P5V
V _{IH}	High-level input voltage	1.2 V to 1.3 V	0.78			V	VIH_1P2V, VIH_1P3V
		1.65 V to 2 V	1.1				VIH_1P65V, VIH_2V
		2.25 V to 2.75 V	1.28				VIH_2P25V, VIH_2P75V
		3 V to 3.6 V	1.45				VIH_3V, VIH_3P6V
		4.5 V to 5.5 V	2				VIH_4P5V, VIH_5P5V
V _{IL}	Low-Level input voltage	1.2 V to 1.3 V			0.18	V	VIL_1P2V, VIL_1P3V
		1.65 V to 2 V			0.51		VIL_1P65V, VIL_2V
		2.25 V to 2.75 V			0.65		VIL_2P25V, VIL_2P75V
		3 V to 3.6 V			0.75		VIL_3V, VIL_3P6V
		4.5 V to 5.5 V			0.80		VIL_4P5V, VIL_5P5V
V _{OH} 2	I _{OH} = -50 μA	1.2 V to 5.5 V	V _{CC} -0.2			V	VOH_N50UA_1P65V, VOH_N50UA_2V, VOH_N50UA_2P75V, VOH_N50UA_3P6V, VOH_N50UA_4P5V, VOH_N50UA_5P5V
	I _{OH} = -1 mA	1.2 V	0.8				VOH_N1MA_1P2V
	I _{OH} = -2 mA	1.65 V to 2 V	1.21				VOH_N2MA_1P65V, VOH_N2MA_2V
	I _{OH} = -3 mA	2.25 V to 2.75 V	1.93				VOH_N3MA_2P25V, VOH_N3MA_2P75V
	I _{OH} = -5.5 mA	3 V to 3.6 V	2.49				VOH_N5P5MA_3V, VOH_N5P5MA_3P6V
	I _{OH} = -8 mA	4.5 V to 5.5 V	3.95				VOH_N8MA_4P5V, VOH_N8MA_5P5V
	I _{OH} = -24 mA	4.5 V to 5.5 V	3.15				VOH_N24MA_4P5V, VOH_N24MA_5P5V

Table 3-1. Electrical Parameters Table (continued)

Parameter	Test Conditions	V _{CC}	T _A = -55°C to +125°C			Unit	Test Name
			MIN	TYP	MAX		
V _{OL}	I _{OL} = 50 µA	1.2 V to 5.5 V		0.1		V	VOL_50UA_1P65V, VOL_50UA_2V, VOL_50UA_2P75V,VOL_50UA_3P6V, VOL_50UA_4P5V, VOL_50UA_5P5V
	I _{OL} = 1 mA	1.2 V		0.2			VOL_1MA_1P2V
	I _{OL} = 2 mA	1.65 V to 2 V		0.25			VOL_2MA_1P65V, VOL_2MA_2V
	I _{OL} = 3 mA	2.25 V to 2.75 V		0.2			VOL_3MA_2P25V, VOL_3MA_2P75V
	I _{OL} = 5.5 mA	3 V to 3.6 V		0.25			VOL_5P5MA_3V, VOL_5P5MA_3P6V
	I _{OL} = 8 mA	4.5 V to 5.5 V		0.35			VOL_8MA_4P5V, VOL_8MA_5P5V
	I _{OL} = 24 mA	4.5 V to 5.5 V		0.75			VOL_24MA_4P5V, VOL_24MA_5P5V
I _{CC}	V _I = V _{CC} or GND, I _O = 0	1.2 V to 5.5 V	2	93	µA		ICCH_5P5V, ICCL_5P5V
ΔI _{CC}	One input at 0.3 V or 3.4 V, other inputs at V _{CC} or GND	5.5 V		1.5	mA		DELTAICC_5P5V
	One input at 0.3 V or 1.1 V, other inputs at V _{CC} or GND	1.8 V		68	µA		DELTAICC_1P8V
I _{OZ} 3	V _O = V _{CC} or GND	5.5 V		±2.5	µA		IOZ
I _I	V _I = 0 V to V _{CC}	V _I = 0 V to V _{CC}		±1	µA		IIH_5P5V, IIL_5P5V

1. Schmitt-trigger input devices only.
2. Push-pull output devices only.
3. 3-State output devices only.

4 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

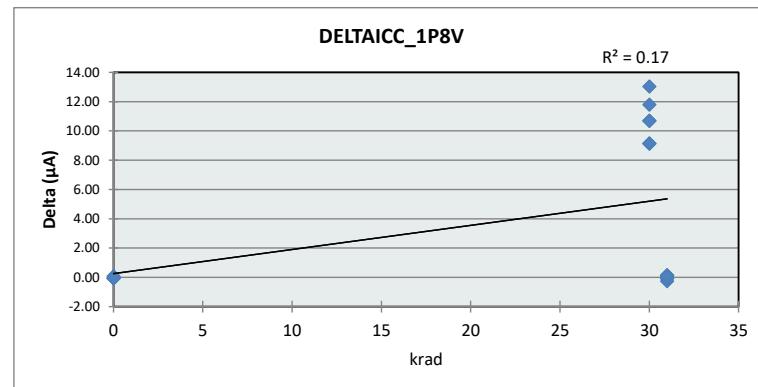
5 Appendix: HDR TID Report Data

This appendix provides the SN54SC3T97-SEP TID HDR report. The report shows the variation for each parameter up to 30 krad(Si).

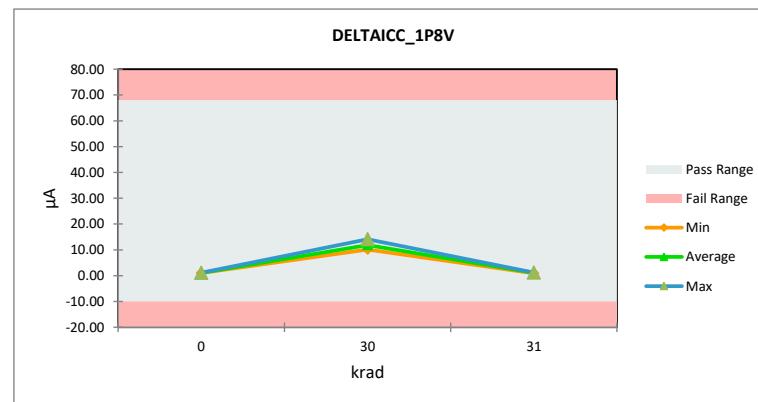
TID Report

SN54SC3T97-SEP

DETAICC_1P8V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	μA					
Max Limit	68					
Min Limit	-10					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.027	0.988	-0.04	-3.79%	0.05%
0	2	1.120	1.051	-0.07	-6.16%	0.09%
0	3	1.027	1.113	0.09	8.37%	0.11%
0	4	1.089	1.051	-0.04	-3.49%	0.05%
30	5	1.151	10.290	9.14	794.01%	11.72%
30	6	1.120	11.820	10.70	955.36%	13.72%
30	7	0.964	10.110	9.15	948.76%	11.73%
30	8	1.058	11.760	10.70	1011.53%	13.72%
30	9	1.058	14.100	13.04	1232.70%	16.72%
30	10	1.151	12.950	11.80	1025.11%	15.13%
31	11	1.151	0.894	-0.26	-22.29%	0.33%
31	12	1.120	1.051	-0.07	-6.16%	0.09%
31	13	0.964	1.113	0.15	15.46%	0.19%
31	14	1.058	1.175	0.12	11.06%	0.15%
31	15	1.058	0.988	-0.07	-6.61%	0.09%
31	16	1.151	1.207	0.06	4.87%	0.07%
Max		1.151	14.100	12.95	1232.70%	16.72%
Average		1.079	5.104	4.02	372.42%	5.25%
Min		0.964	0.894	-0.07	-22.29%	0.05%
Std Dev		0.063	5.460	5.40	504.57%	6.93%



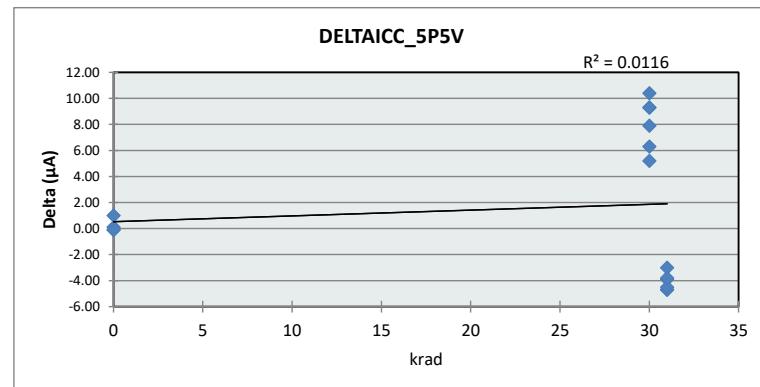
DETAICC_1P8V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	μA					
Max Limit	68					
Min Limit	-10					
krad	0	30	31			
LL	-10.00	-10.00	-10.00			
Min	0.99	10.11	0.89			
Average	1.05	11.84	1.07			
Max	1.11	14.10	1.21			
UL	68.00	68.00	68.00			



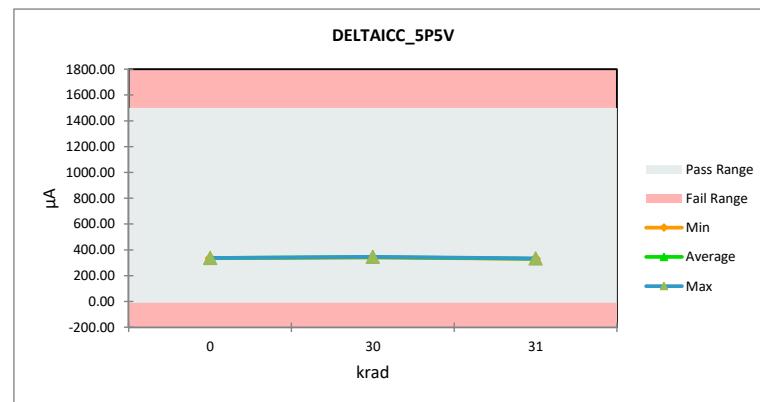
TID Report

SN54SC3T97-SEP

DETAICC_5P5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	μA					
Max Limit	1500					
Min Limit	-10					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	335.200	336.200	1.00	0.30%	0.07%
0	2	336.400	336.500	0.10	0.03%	0.01%
0	3	335.400	335.300	-0.10	-0.03%	0.01%
0	4	335.600	335.500	-0.10	-0.03%	0.01%
30	5	333.900	341.800	7.90	2.37%	0.52%
30	6	334.300	340.600	6.30	1.88%	0.42%
30	7	336.300	341.500	5.20	1.55%	0.34%
30	8	336.400	345.700	9.30	2.76%	0.62%
30	9	334.400	344.800	10.40	3.11%	0.69%
30	10	334.500	343.800	9.30	2.78%	0.62%
31	11	333.900	330.000	-3.90	-1.17%	0.26%
31	12	334.300	329.600	-4.70	-1.41%	0.31%
31	13	336.300	333.300	-3.00	-0.89%	0.20%
31	14	336.400	331.700	-4.70	-1.40%	0.31%
31	15	334.400	329.900	-4.50	-1.35%	0.30%
31	16	334.500	330.700	-3.80	-1.14%	0.25%
Max		336.400	345.700	9.30	3.11%	0.69%
Average		335.138	336.681	1.54	0.46%	0.31%
Min		333.900	329.600	-4.30	-1.41%	0.01%
Std Dev		0.971	5.651	4.68	1.68%	0.22%



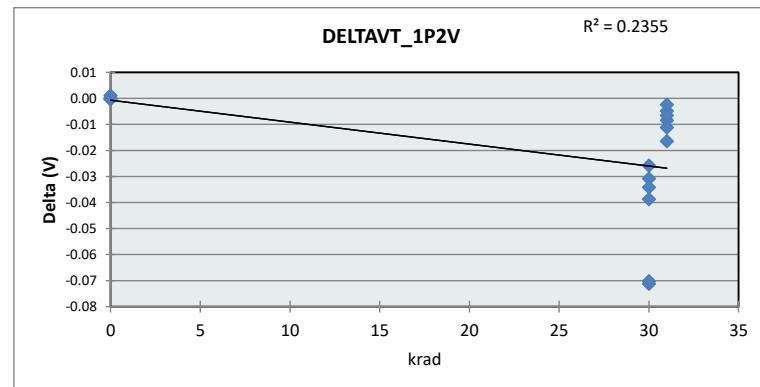
DETAICC_5P5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	μA					
Max Limit	1500					
Min Limit	-10					
krad	0	30	31			
LL	-10.00	-10.00	-10.00			
Min	335.30	340.60	329.60			
Average	335.88	343.03	330.87			
Max	336.50	345.70	333.30			
UL	1500.00	1500.00	1500.00			



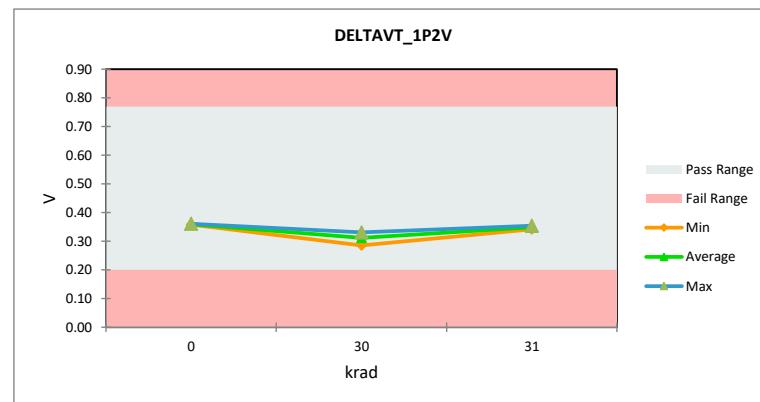
TID Report

SN54SC3T97-SEP

DELTAVT_1P2V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.77					
Min Limit	0.2					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.359	0.360	0.00	0.32%	0.20%
0	2	0.361	0.361	0.00	0.06%	0.04%
0	3	0.358	0.358	0.00	-0.03%	0.02%
0	4	0.358	0.358	0.00	-0.09%	0.06%
30	5	0.355	0.325	-0.03	-8.65%	5.39%
30	6	0.358	0.324	-0.03	-9.53%	6.00%
30	7	0.358	0.286	-0.07	-19.92%	12.50%
30	8	0.356	0.285	-0.07	-19.75%	12.32%
30	9	0.357	0.331	-0.03	-7.24%	4.53%
30	10	0.358	0.319	-0.04	-10.82%	6.79%
31	11	0.355	0.347	-0.01	-2.37%	1.48%
31	12	0.358	0.354	0.00	-1.34%	0.84%
31	13	0.358	0.346	-0.01	-3.12%	1.96%
31	14	0.356	0.349	-0.01	-1.84%	1.15%
31	15	0.357	0.354	0.00	-0.68%	0.43%
31	16	0.358	0.341	-0.02	-4.59%	2.88%
Max		0.361	0.361	0.00	0.32%	12.50%
Average		0.357	0.337	-0.02	-5.60%	3.54%
Min		0.355	0.285	-0.07	-19.92%	0.02%
Std Dev		0.001	0.024	0.02	6.65%	4.13%



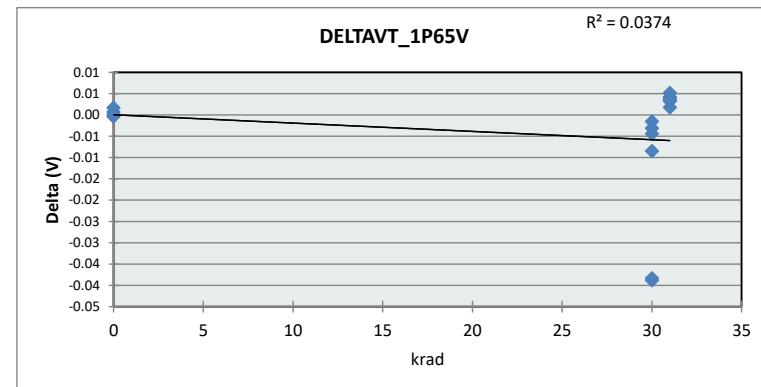
DELTAVT_1P2V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.77					
Min Limit	0.2					
krad	0	30	31			
LL	0.20	0.20	0.20			
Min	0.36	0.29	0.34			
Average	0.36	0.31	0.35			
Max	0.36	0.33	0.35			
UL	0.77	0.77	0.77			



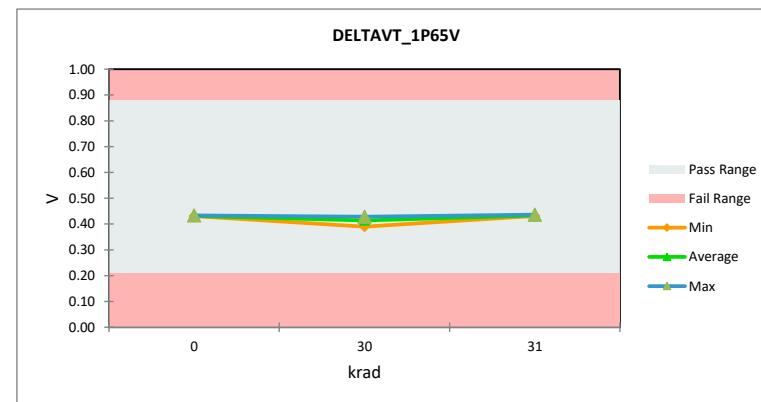
TID Report

SN54SC3T97-SEP

DELTAVT_1P65V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.88					
Min Limit	0.21					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.431	0.431	0.00	0.16%	0.10%
0	2	0.432	0.433	0.00	0.40%	0.26%
0	3	0.432	0.432	0.00	-0.08%	0.05%
0	4	0.430	0.430	0.00	0.01%	0.01%
30	5	0.427	0.424	0.00	-0.72%	0.46%
30	6	0.431	0.427	0.00	-1.02%	0.65%
30	7	0.430	0.391	-0.04	-9.03%	5.79%
30	8	0.428	0.390	-0.04	-8.95%	5.72%
30	9	0.430	0.428	0.00	-0.35%	0.22%
30	10	0.432	0.423	-0.01	-1.96%	1.26%
31	11	0.427	0.431	0.00	0.99%	0.63%
31	12	0.431	0.436	0.01	1.20%	0.77%
31	13	0.430	0.432	0.00	0.41%	0.27%
31	14	0.428	0.431	0.00	0.76%	0.49%
31	15	0.430	0.434	0.00	0.89%	0.57%
31	16	0.432	0.435	0.00	0.78%	0.51%
Max		0.432	0.436	0.00	1.20%	5.79%
Average		0.430	0.426	0.00	-1.03%	1.11%
Min		0.427	0.390	-0.04	-9.03%	0.01%
Std Dev		0.002	0.014	0.01	3.21%	1.84%



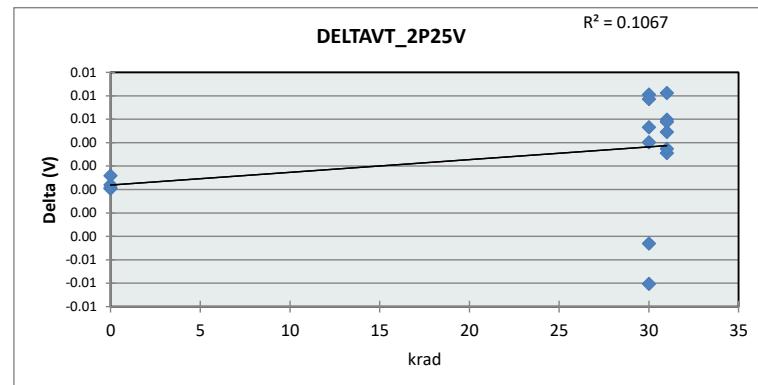
DELTAVT_1P65V								
Test Site	CLAB							
Tester	ETS88-01							
Test Number	EQ774601							
Units	V							
Max Limit	0.88							
Min Limit	0.21							
krad	0	30	31	LL	0.21			
				Min	0.43			
Average	0.43							
Max	0.43							
UL	0.88							



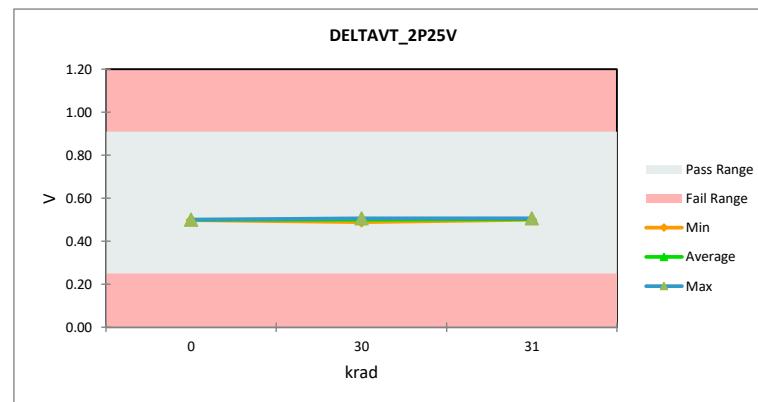
TID Report

SN54SC3T97-SEP

DELTAVT_2P25V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.91					
Min Limit	0.25					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.500	0.500	0.00	0.08%	0.06%
0	2	0.499	0.500	0.00	0.24%	0.18%
0	3	0.500	0.500	0.00	0.03%	0.02%
0	4	0.498	0.498	0.00	0.01%	0.01%
30	5	0.495	0.503	0.01	1.64%	1.23%
30	6	0.498	0.506	0.01	1.55%	1.17%
30	7	0.498	0.493	0.00	-0.92%	0.70%
30	8	0.497	0.489	-0.01	-1.62%	1.22%
30	9	0.499	0.504	0.01	1.07%	0.81%
30	10	0.499	0.503	0.00	0.81%	0.61%
31	11	0.495	0.501	0.01	1.20%	0.90%
31	12	0.498	0.507	0.01	1.65%	1.25%
31	13	0.498	0.502	0.00	0.99%	0.74%
31	14	0.497	0.500	0.00	0.63%	0.47%
31	15	0.499	0.502	0.00	0.70%	0.53%
31	16	0.499	0.505	0.01	1.16%	0.88%
Max		0.500	0.507	0.01	1.65%	1.25%
Average		0.498	0.501	0.00	0.58%	0.67%
Min		0.495	0.489	-0.01	-1.62%	0.01%
Std Dev		0.002	0.005	0.00	0.91%	0.44%



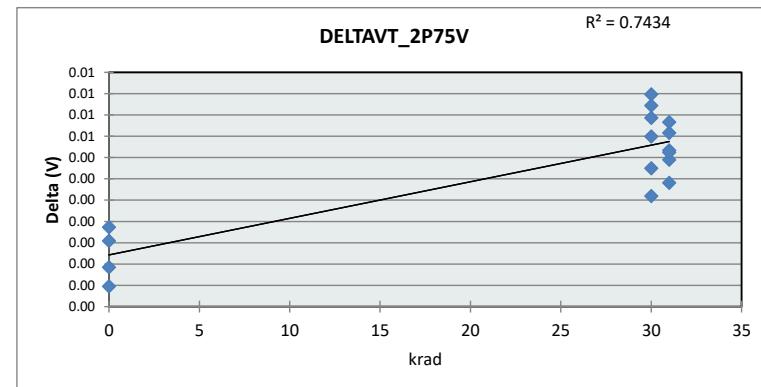
DELTAVT_2P25V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.91					
Min Limit	0.25					
krad	0	30	31			
LL	0.25	0.25	0.25			
Min	0.50	0.49	0.50			
Average	0.50	0.50	0.50			
Max	0.50	0.51	0.51			
UL	0.91	0.91	0.91			



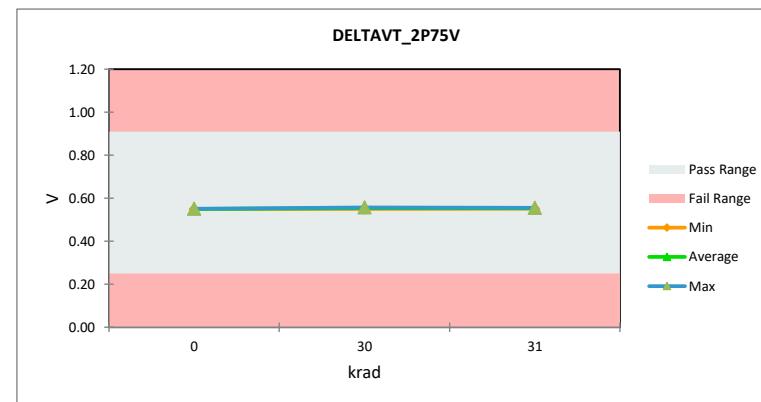
TID Report

SN54SC3T97-SEP

DELTAVT_2P75V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.91					
Min Limit	0.25					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.551	0.551	0.00	0.02%	0.01%
0	2	0.552	0.551	0.00	-0.21%	0.17%
0	3	0.552	0.550	0.00	-0.37%	0.31%
0	4	0.549	0.549	0.00	0.13%	0.11%
30	5	0.546	0.553	0.01	1.28%	1.06%
30	6	0.550	0.555	0.01	1.07%	0.89%
30	7	0.547	0.552	0.00	0.91%	0.76%
30	8	0.548	0.550	0.00	0.40%	0.33%
30	9	0.550	0.554	0.00	0.64%	0.53%
30	10	0.551	0.557	0.01	1.17%	0.98%
31	11	0.546	0.551	0.01	0.94%	0.78%
31	12	0.550	0.555	0.01	1.03%	0.86%
31	13	0.547	0.552	0.00	0.79%	0.66%
31	14	0.548	0.552	0.00	0.71%	0.59%
31	15	0.550	0.553	0.00	0.51%	0.43%
31	16	0.551	0.555	0.00	0.77%	0.64%
Max		0.552	0.557	0.01	1.28%	1.06%
Average		0.549	0.553	0.00	0.61%	0.57%
Min		0.546	0.549	0.00	-0.37%	0.01%
Std Dev		0.002	0.002	0.00	0.50%	0.32%



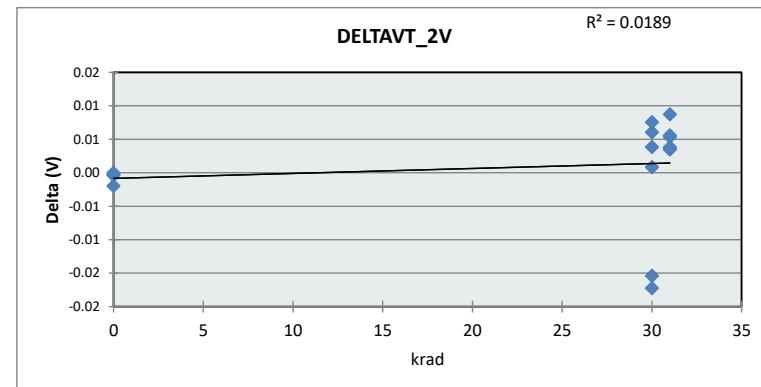
DELTAVT_2P75V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.91					
Min Limit	0.25					
krad	0	30	31			
LL	0.25	0.25	0.25			
Min	0.55	0.55	0.55			
Average	0.55	0.55	0.55			
Max	0.55	0.56	0.56			
UL	0.91	0.91	0.91			



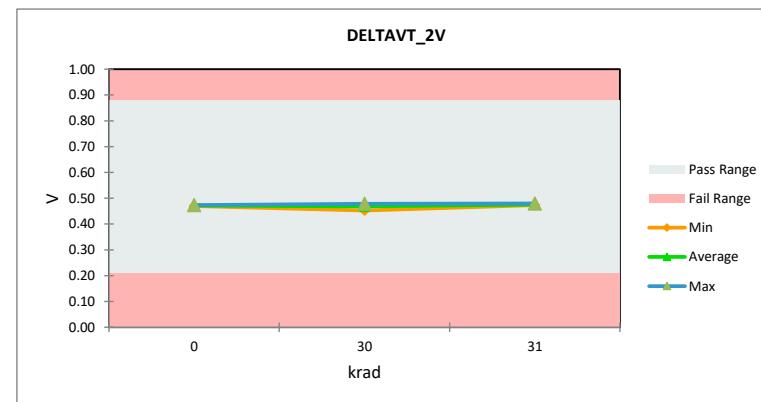
TID Report

SN54SC3T97-SEP

DELTAVT_2V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.88					
Min Limit	0.21					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.474	0.473	0.00	-0.08%	0.06%
0	2	0.473	0.473	0.00	-0.06%	0.04%
0	3	0.471	0.471	0.00	0.00%	0.00%
0	4	0.472	0.470	0.00	-0.42%	0.29%
30	5	0.468	0.474	0.01	1.30%	0.91%
30	6	0.471	0.478	0.01	1.61%	1.13%
30	7	0.471	0.456	-0.02	-3.27%	2.30%
30	8	0.469	0.452	-0.02	-3.67%	2.57%
30	9	0.472	0.475	0.00	0.82%	0.57%
30	10	0.472	0.473	0.00	0.18%	0.13%
31	11	0.468	0.474	0.01	1.14%	0.80%
31	12	0.471	0.480	0.01	1.85%	1.30%
31	13	0.471	0.474	0.00	0.76%	0.53%
31	14	0.469	0.473	0.00	0.82%	0.57%
31	15	0.472	0.475	0.00	0.74%	0.52%
31	16	0.472	0.478	0.01	1.18%	0.83%
Max		0.474	0.480	0.01	1.85%	2.57%
Average		0.471	0.472	0.00	0.18%	0.78%
Min		0.468	0.452	-0.02	-3.67%	0.00%
Std Dev		0.002	0.007	0.01	1.56%	0.75%



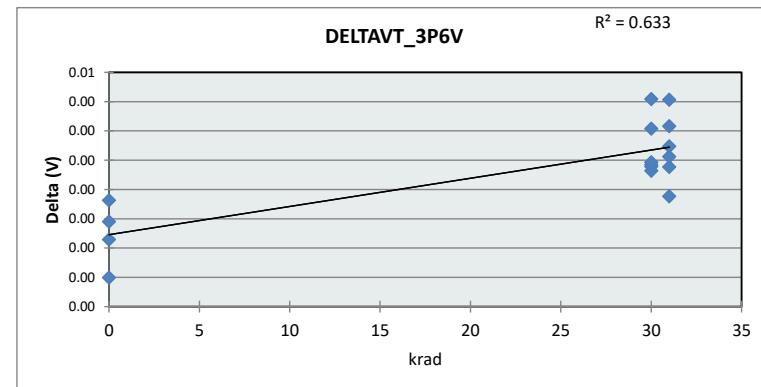
DELTAVT_2V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.88					
Min Limit	0.21					
krad	0	30	31			
LL	0.21	0.21	0.21			
Min	0.47	0.45	0.47			
Average	0.47	0.47	0.48			
Max	0.47	0.48	0.48			
UL	0.88	0.88	0.88			



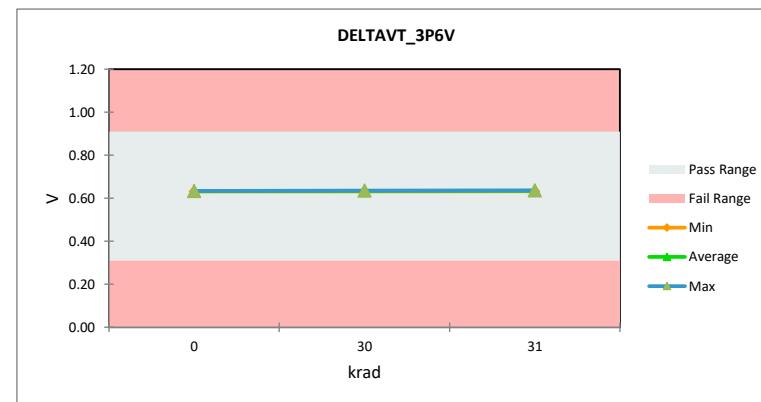
TID Report

SN54SC3T97-SEP

DELTAVT_3P6V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.91					
Min Limit	0.31					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.633	0.633	0.00	-0.02%	0.02%
0	2	0.633	0.631	0.00	-0.32%	0.33%
0	3	0.635	0.634	0.00	-0.11%	0.12%
0	4	0.631	0.632	0.00	0.10%	0.10%
30	5	0.630	0.632	0.00	0.29%	0.31%
30	6	0.631	0.635	0.00	0.65%	0.68%
30	7	0.631	0.634	0.00	0.49%	0.51%
30	8	0.632	0.634	0.00	0.26%	0.27%
30	9	0.633	0.635	0.00	0.28%	0.30%
30	10	0.633	0.635	0.00	0.31%	0.32%
31	11	0.630	0.632	0.00	0.39%	0.41%
31	12	0.631	0.635	0.00	0.64%	0.68%
31	13	0.631	0.632	0.00	0.28%	0.30%
31	14	0.632	0.633	0.00	0.12%	0.13%
31	15	0.633	0.635	0.00	0.34%	0.35%
31	16	0.633	0.636	0.00	0.50%	0.53%
Max		0.635	0.636	0.00	0.65%	0.68%
Average		0.632	0.634	0.00	0.26%	0.34%
Min		0.630	0.631	0.00	-0.32%	0.02%
Std Dev		0.001	0.002	0.00	0.26%	0.19%



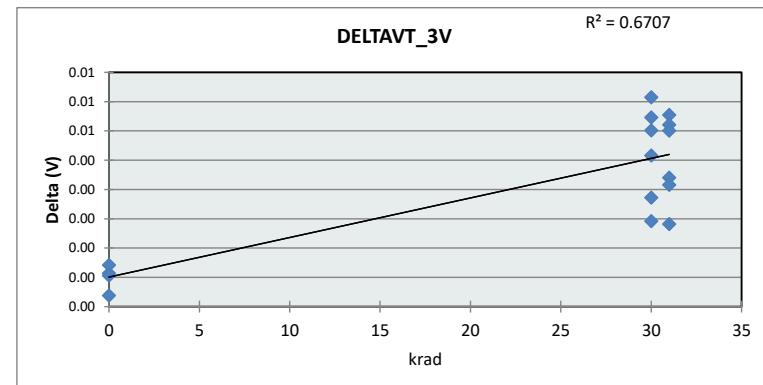
DELTAVT_3P6V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.91					
Min Limit	0.31					
Max	0	30	31			
LL	0.31	0.31	0.31			
Min	0.63	0.63	0.63			
Average	0.63	0.63	0.63			
Max	0.63	0.64	0.64			
UL	0.91	0.91	0.91			



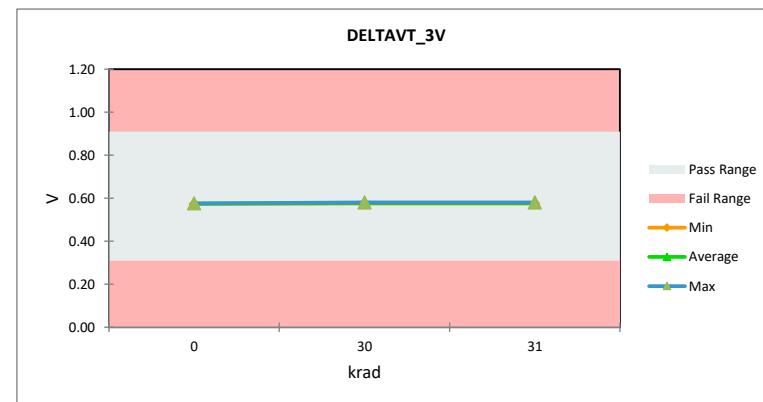
TID Report

SN54SC3T97-SEP

DELTAVT_3V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.91					
Min Limit	0.31					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.575	0.574	0.00	-0.11%	0.10%
0	2	0.575	0.575	0.00	0.02%	0.02%
0	3	0.575	0.576	0.00	0.07%	0.07%
0	4	0.573	0.574	0.00	0.01%	0.01%
30	5	0.571	0.576	0.01	0.96%	0.91%
30	6	0.574	0.580	0.01	1.07%	1.03%
30	7	0.572	0.576	0.00	0.73%	0.69%
30	8	0.573	0.575	0.00	0.34%	0.32%
30	9	0.575	0.578	0.00	0.47%	0.45%
30	10	0.575	0.580	0.01	0.87%	0.84%
31	11	0.571	0.576	0.01	0.97%	0.92%
31	12	0.574	0.579	0.01	0.91%	0.87%
31	13	0.572	0.576	0.00	0.59%	0.57%
31	14	0.573	0.575	0.00	0.32%	0.30%
31	15	0.575	0.578	0.00	0.55%	0.53%
31	16	0.575	0.580	0.01	0.87%	0.83%
Max		0.575	0.580	0.00	1.07%	1.03%
Average		0.574	0.577	0.00	0.54%	0.53%
Min		0.571	0.574	0.00	-0.11%	0.01%
Std Dev		0.002	0.002	0.00	0.39%	0.36%



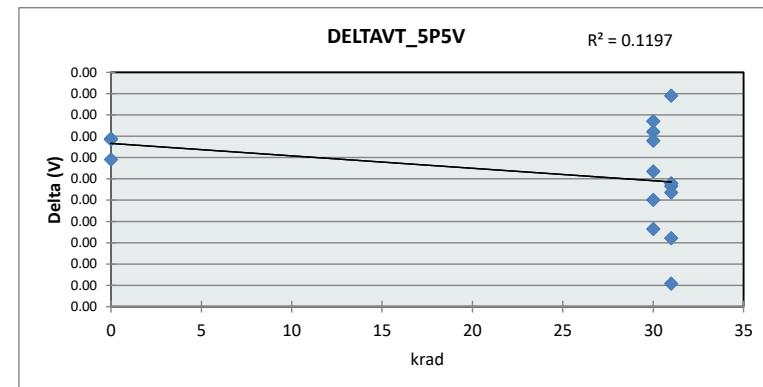
DELTAVT_3V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.91					
Min Limit	0.31					
krad	0	30	31			
LL	0.31	0.31	0.31			
Min	0.57	0.58	0.58			
Average	0.57	0.58	0.58			
Max	0.58	0.58	0.58			
UL	0.91	0.91	0.91			



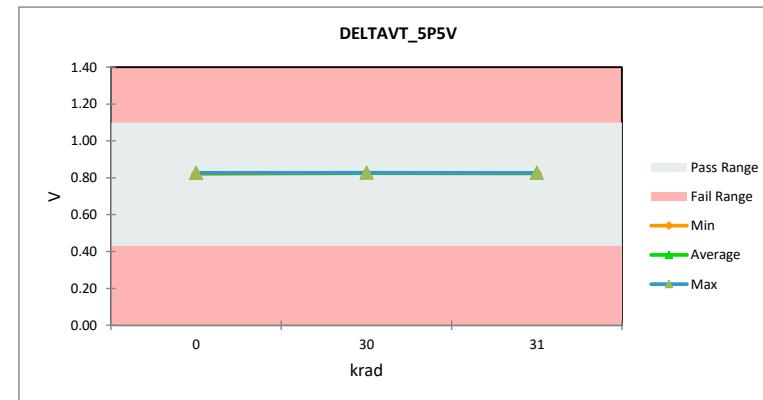
TID Report

SN54SC3T97-SEP

DELTAVT_5P5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.1					
Min Limit	0.43					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.827	0.827	0.00	-0.01%	0.01%
0	2	0.821	0.821	0.00	-0.01%	0.01%
0	3	0.825	0.824	0.00	-0.07%	0.08%
0	4	0.827	0.827	0.00	-0.01%	0.01%
30	5	0.824	0.824	0.00	0.01%	0.02%
30	6	0.826	0.826	0.00	0.04%	0.05%
30	7	0.827	0.826	0.00	-0.18%	0.22%
30	8	0.827	0.826	0.00	-0.10%	0.12%
30	9	0.827	0.827	0.00	-0.01%	0.02%
30	10	0.827	0.825	0.00	-0.26%	0.33%
31	11	0.824	0.823	0.00	-0.14%	0.18%
31	12	0.826	0.827	0.00	0.12%	0.14%
31	13	0.827	0.825	0.00	-0.29%	0.36%
31	14	0.827	0.826	0.00	-0.13%	0.16%
31	15	0.827	0.826	0.00	-0.16%	0.20%
31	16	0.827	0.824	0.00	-0.42%	0.52%
Max		0.827	0.827	0.00	0.12%	0.52%
Average		0.826	0.825	0.00	-0.10%	0.15%
Min		0.821	0.821	0.00	-0.42%	0.01%
Std Dev		0.002	0.002	0.00	0.14%	0.15%



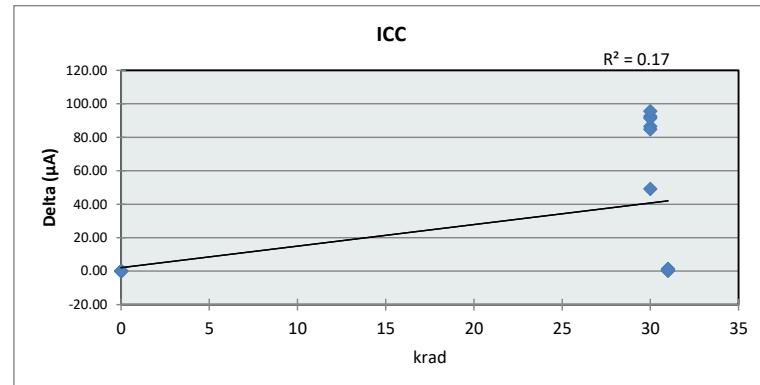
DELTAVT_5P5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.1					
Min Limit	0.43					
Max	0	30	31			
LL	0.43	0.43	0.43			
Min	0.82	0.82	0.82			
Average	0.82	0.83	0.83			
Max	0.83	0.83	0.83			
UL	1.10	1.10	1.10			



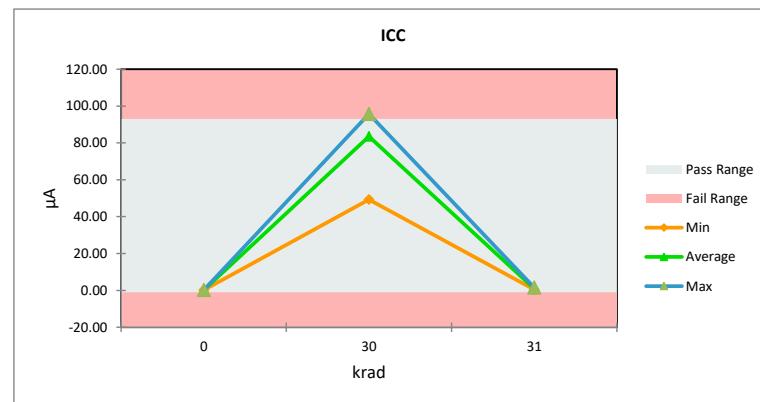
TID Report

SN54SC3T97-SEP

ICC						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	μA					
Max Limit	93					
Min Limit	-1					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.145	0.142	0.00	-2.34%	0.00%
0	2	0.141	0.145	0.00	2.91%	0.00%
0	3	0.134	0.171	0.04	27.79%	0.04%
0	4	0.112	0.144	0.03	28.29%	0.03%
30	5	0.147	86.730	86.58	58779.84%	92.11%
30	6	0.152	92.680	92.53	60873.68%	98.43%
30	7	0.125	84.970	84.85	67876.00%	90.26%
30	8	0.110	91.660	91.55	83303.09%	97.39%
30	9	0.129	49.260	49.13	38145.34%	52.27%
30	10	0.140	95.720	95.58	68076.64%	101.68%
31	11	0.147	0.551	0.40	273.73%	0.43%
31	12	0.152	1.049	0.90	590.13%	0.95%
31	13	0.125	0.529	0.40	323.28%	0.43%
31	14	0.110	0.417	0.31	279.62%	0.33%
31	15	0.129	1.217	1.09	844.88%	1.16%
31	16	0.140	1.535	1.39	993.30%	1.48%
Max		0.152	95.720	95.57	83303.09%	101.68%
Average		0.134	31.682	31.55	23776.01%	33.56%
Min		0.110	0.142	0.03	-2.34%	0.00%
Std Dev		0.014	42.636	42.62	32408.08%	45.36%



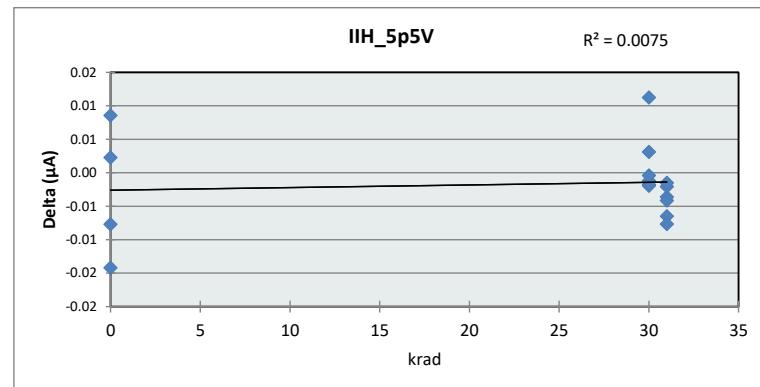
ICC						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	μA					
Max Limit	93					
Min Limit	-1					
krad	0	30	31			
LL	-1.00	-1.00	-1.00			
Min	0.14	49.26	0.42			
Average	0.15	83.50	0.88			
Max	0.17	95.72	1.54			
UL	93.00	93.00	93.00			



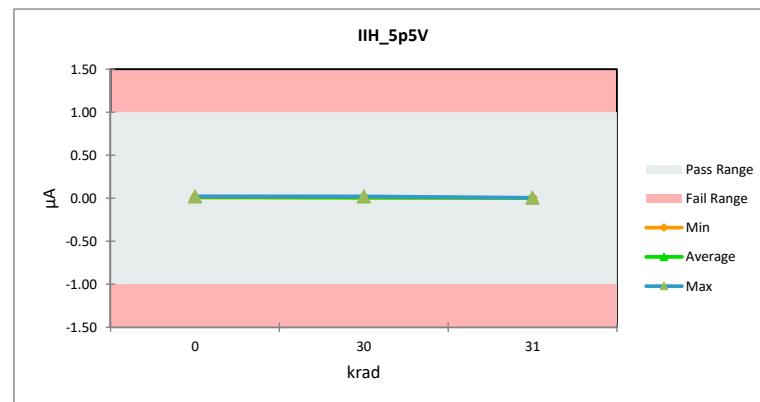
TID Report

SN54SC3T97-SEP

IIH_5p5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	μA					
Max Limit	1					
Min Limit	-1					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.016	0.008	-0.01	-48.24%	0.38%
0	2	0.032	0.017	-0.01	-44.83%	0.71%
0	3	0.013	0.022	0.01	63.72%	0.43%
0	4	0.007	0.009	0.00	34.06%	0.11%
30	5	0.009	0.020	0.01	128.14%	0.56%
30	6	0.010	0.008	0.00	-19.85%	0.10%
30	7	0.007	0.006	0.00	-16.21%	0.06%
30	8	0.005	0.008	0.00	65.92%	0.16%
30	9	0.010	0.009	0.00	-16.97%	0.09%
30	10	0.006	0.005	0.00	-6.85%	0.02%
31	11	0.009	0.005	0.00	-41.19%	0.18%
31	12	0.010	0.003	-0.01	-66.70%	0.32%
31	13	0.007	0.003	0.00	-55.43%	0.21%
31	14	0.005	0.003	0.00	-43.73%	0.10%
31	15	0.010	0.003	-0.01	-74.10%	0.38%
31	16	0.006	0.004	0.00	-25.66%	0.07%
Max		0.032	0.022	-0.01	128.14%	0.71%
Average		0.010	0.008	0.00	-10.50%	0.24%
Min		0.005	0.003	0.00	-74.10%	0.02%
Std Dev		0.006	0.006	0.00	55.88%	0.20%



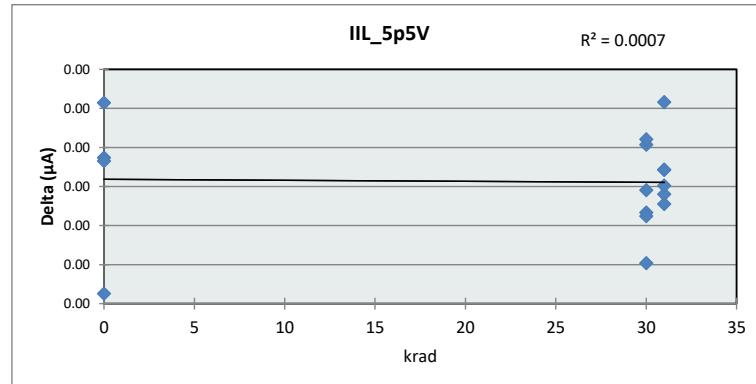
IIH_5p5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	μA					
Max Limit	1					
Min Limit	-1					
krad	0	30	31			
LL	-1.00	-1.00	-1.00			
Min	0.01	0.01	0.00			
Average	0.01	0.01	0.00			
Max	0.02	0.02	0.01			
UL	1.00	1.00	1.00			



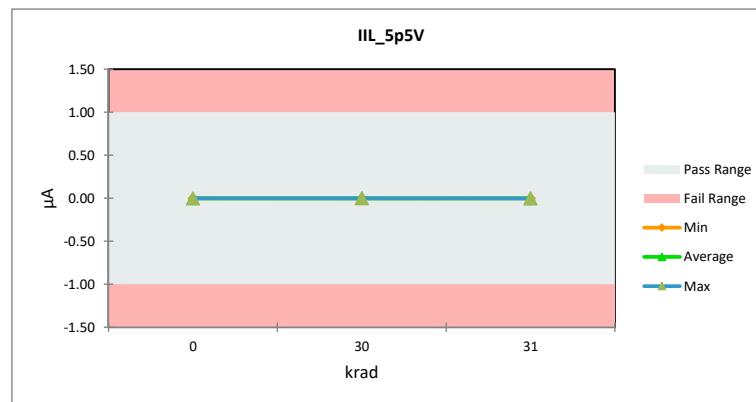
TID Report

SN54SC3T97-SEP

III_L_5p5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	μA					
Max Limit	1					
Min Limit	-1					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	-0.001	-0.001	0.00	4.02%	0.00%
0	2	-0.001	-0.001	0.00	5.68%	0.00%
0	3	-0.001	-0.002	0.00	78.77%	0.04%
0	4	-0.001	-0.001	0.00	-17.28%	0.01%
30	5	-0.001	-0.001	0.00	-1.07%	0.00%
30	6	-0.001	-0.001	0.00	43.64%	0.02%
30	7	-0.001	-0.002	0.00	58.54%	0.03%
30	8	-0.001	-0.001	0.00	23.00%	0.01%
30	9	-0.001	-0.001	0.00	-4.28%	0.00%
30	10	-0.001	-0.001	0.00	32.74%	0.02%
31	11	-0.001	-0.001	0.00	-16.62%	0.01%
31	12	-0.001	-0.001	0.00	31.32%	0.01%
31	13	-0.001	-0.001	0.00	19.25%	0.01%
31	14	-0.001	-0.001	0.00	11.95%	0.01%
31	15	-0.001	-0.001	0.00	29.48%	0.01%
31	16	-0.001	-0.001	0.00	10.60%	0.01%
Max		-0.001	-0.001	0.00	78.77%	0.04%
Average		-0.001	-0.001	0.00	19.36%	0.01%
Min		-0.001	-0.002	0.00	-17.28%	0.00%
Std Dev		0.000	0.000	0.00	26.15%	0.01%



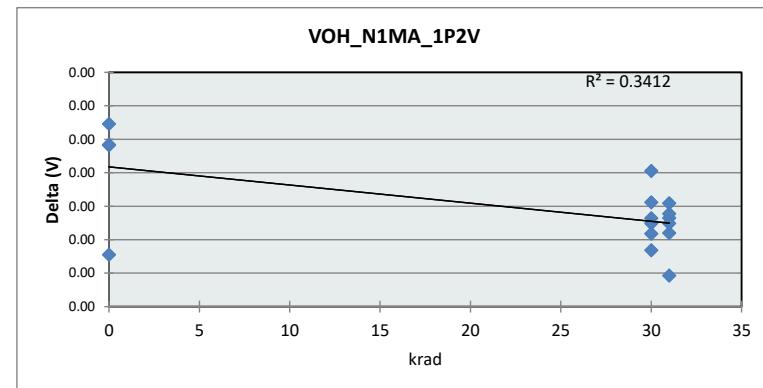
III_L_5p5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	μA					
Max Limit	1					
Min Limit	-1					
krad	0	30	31			
LL	-1.00	-1.00	-1.00			
Min	0.00	0.00	0.00			
Average	0.00	0.00	0.00			
Max	0.00	0.00	0.00			
UL	1.00	1.00	1.00			



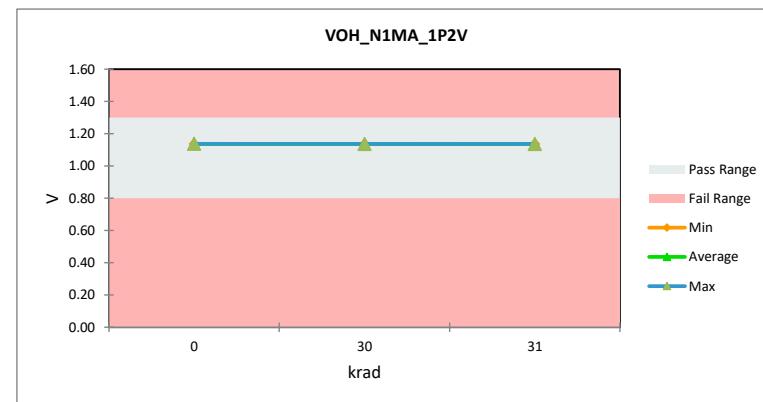
TID Report

SN54SC3T97-SEP

VOH_N1MA_1P2V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.3					
Min Limit	0.8					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.137	1.136	0.00	-0.10%	0.22%
0	2	1.138	1.137	0.00	-0.03%	0.06%
0	3	1.137	1.137	0.00	-0.04%	0.09%
0	4	1.137	1.137	0.00	-0.04%	0.09%
30	5	1.137	1.136	0.00	-0.07%	0.16%
30	6	1.137	1.136	0.00	-0.05%	0.12%
30	7	1.137	1.136	0.00	-0.08%	0.17%
30	8	1.137	1.137	0.00	-0.08%	0.18%
30	9	1.137	1.136	0.00	-0.09%	0.21%
30	10	1.137	1.136	0.00	-0.08%	0.19%
31	11	1.137	1.136	0.00	-0.07%	0.16%
31	12	1.137	1.136	0.00	-0.08%	0.17%
31	13	1.137	1.136	0.00	-0.08%	0.19%
31	14	1.137	1.137	0.00	-0.07%	0.17%
31	15	1.137	1.136	0.00	-0.08%	0.18%
31	16	1.137	1.136	0.00	-0.11%	0.24%
Max		1.138	1.137	0.00	-0.03%	0.24%
Average		1.137	1.136	0.00	-0.07%	0.16%
Min		1.137	1.136	0.00	-0.11%	0.06%
Std Dev		0.000	0.000	0.00	0.02%	0.05%



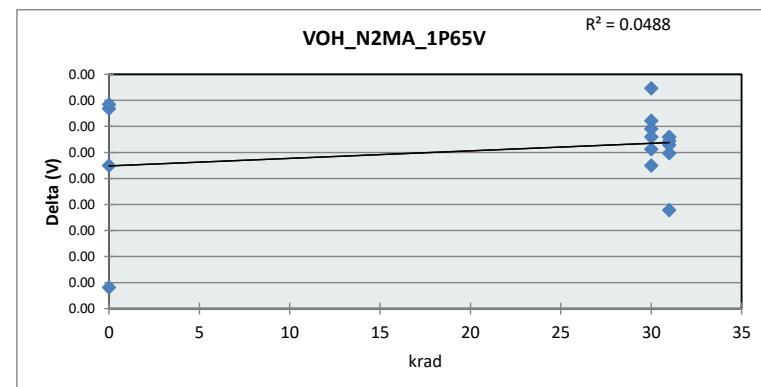
VOH_N1MA_1P2V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.3					
Min Limit	0.8					
krad	0	30	31			
LL	0.80	0.80	0.80			
Min	1.14	1.14	1.14			
Average	1.14	1.14	1.14			
Max	1.14	1.14	1.14			
UL	1.30	1.30	1.30			



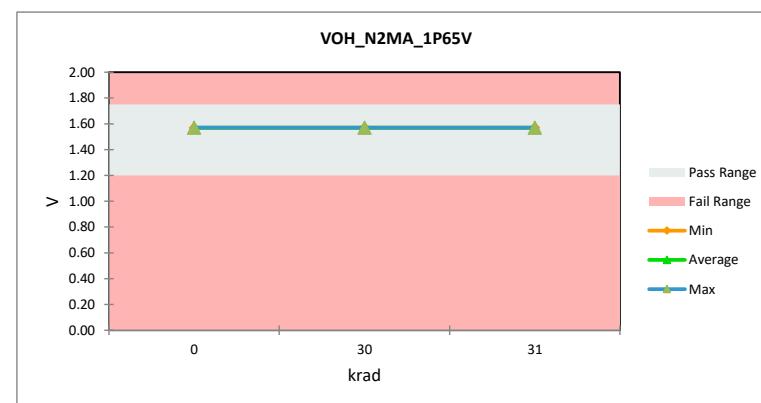
TID Report

SN54SC3T97-SEP

VOH_N2MA_1P65V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.570	1.569	0.00	-0.10%	0.30%
0	2	1.571	1.570	0.00	-0.02%	0.05%
0	3	1.570	1.570	0.00	-0.01%	0.04%
0	4	1.571	1.570	0.00	-0.04%	0.13%
30	5	1.570	1.570	0.00	-0.01%	0.02%
30	6	1.570	1.570	0.00	-0.02%	0.06%
30	7	1.570	1.570	0.00	-0.03%	0.08%
30	8	1.570	1.570	0.00	-0.03%	0.09%
30	9	1.570	1.570	0.00	-0.04%	0.10%
30	10	1.570	1.570	0.00	-0.04%	0.13%
31	11	1.570	1.570	0.00	-0.03%	0.09%
31	12	1.570	1.570	0.00	-0.03%	0.09%
31	13	1.570	1.570	0.00	-0.04%	0.11%
31	14	1.570	1.570	0.00	-0.03%	0.10%
31	15	1.570	1.570	0.00	-0.03%	0.09%
31	16	1.570	1.569	0.00	-0.07%	0.19%
Max		1.571	1.570	0.00	-0.01%	0.30%
Average		1.570	1.570	0.00	-0.04%	0.10%
Min		1.570	1.569	0.00	-0.10%	0.02%
Std Dev		0.000	0.000	0.00	0.02%	0.06%



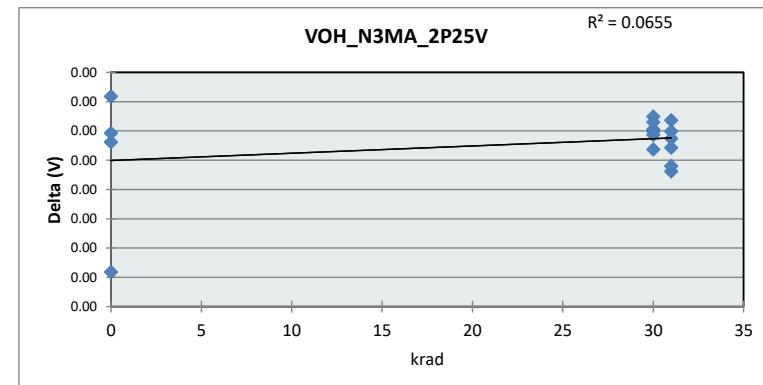
VOH_N2MA_1P65V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
krad	0	30	31	LL	Min	Average
Max	1.571	1.570	1.570	1.20	1.20	1.20
Average	1.570	1.570	1.570	1.57	1.57	1.57
Min	1.570	1.569	1.569	1.57	1.57	1.57
UL	1.570	1.570	1.570	1.75	1.75	1.75



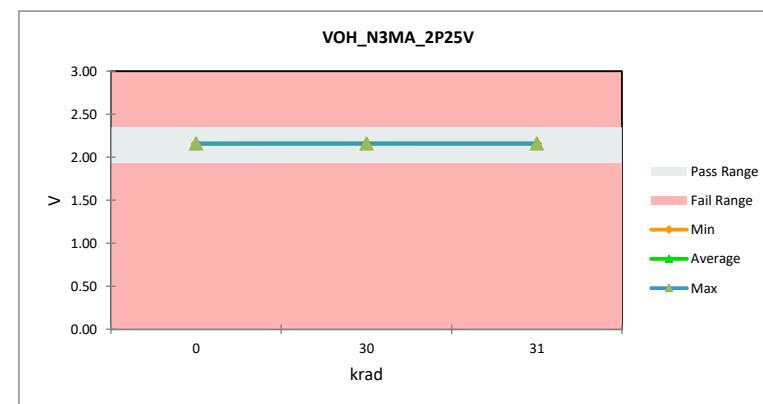
TID Report

SN54SC3T97-SEP

VOH_N3MA_2P25V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	2.35					
Min Limit	1.93					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	2.159	2.156	0.00	-0.13%	0.69%
0	2	2.159	2.159	0.00	0.00%	0.02%
0	3	2.159	2.158	0.00	-0.03%	0.16%
0	4	2.159	2.159	0.00	-0.02%	0.13%
30	5	2.159	2.159	0.00	-0.02%	0.12%
30	6	2.159	2.159	0.00	-0.01%	0.06%
30	7	2.159	2.158	0.00	-0.02%	0.11%
30	8	2.159	2.159	0.00	-0.03%	0.14%
30	9	2.159	2.158	0.00	-0.04%	0.19%
30	10	2.159	2.158	0.00	-0.02%	0.08%
31	11	2.159	2.158	0.00	-0.04%	0.19%
31	12	2.159	2.159	0.00	-0.01%	0.08%
31	13	2.159	2.158	0.00	-0.02%	0.12%
31	14	2.159	2.158	0.00	-0.06%	0.28%
31	15	2.159	2.159	0.00	-0.03%	0.15%
31	16	2.159	2.158	0.00	-0.05%	0.26%
Max		2.159	2.159	0.00	0.00%	0.69%
Average		2.159	2.158	0.00	-0.03%	0.17%
Min		2.159	2.156	0.00	-0.13%	0.02%
Std Dev		0.000	0.001	0.00	0.03%	0.15%



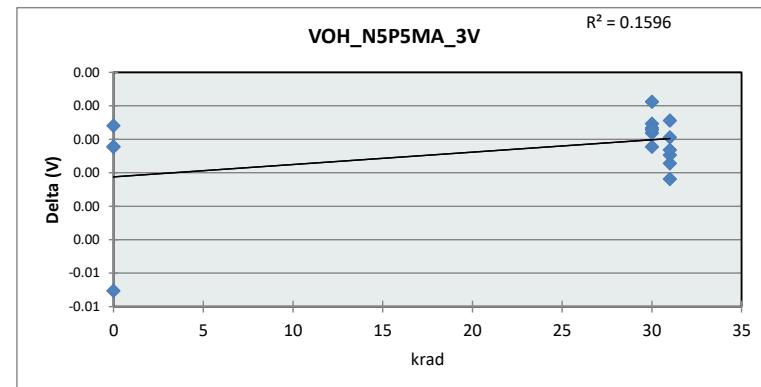
VOH_N3MA_2P25V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	2.35					
Min Limit	1.93					
krad	0	30	31			
LL	1.93	1.93	1.93			
Min	2.16	2.16	2.16			
Average	2.16	2.16	2.16			
Max	2.16	2.16	2.16			
UL	2.35	2.35	2.35			



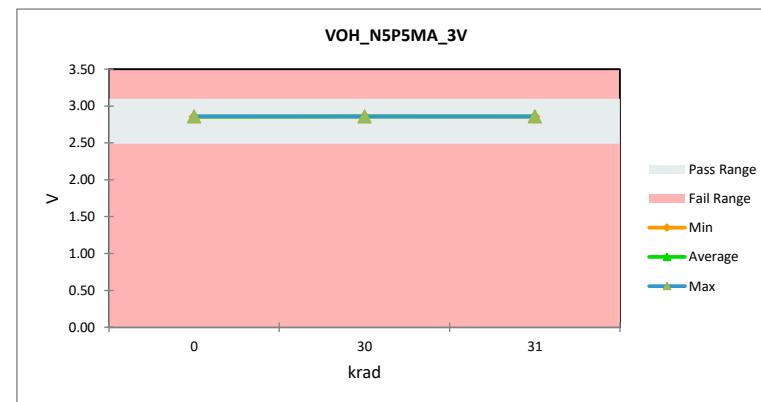
TID Report

SN54SC3T97-SEP

VOH_N5P5MA_3V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	3.1					
Min Limit	2.49					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	2.860	2.855	-0.01	-0.19%	0.91%
0	2	2.860	2.859	0.00	-0.02%	0.10%
0	3	2.860	2.859	0.00	-0.04%	0.20%
0	4	2.860	2.859	0.00	-0.04%	0.20%
30	5	2.860	2.859	0.00	-0.02%	0.09%
30	6	2.859	2.859	0.00	0.00%	0.02%
30	7	2.860	2.859	0.00	-0.03%	0.13%
30	8	2.860	2.859	0.00	-0.02%	0.11%
30	9	2.860	2.859	0.00	-0.04%	0.20%
30	10	2.859	2.859	0.00	-0.03%	0.12%
31	11	2.860	2.859	0.00	-0.03%	0.15%
31	12	2.859	2.859	0.00	-0.02%	0.07%
31	13	2.860	2.858	0.00	-0.05%	0.24%
31	14	2.860	2.858	0.00	-0.06%	0.28%
31	15	2.860	2.859	0.00	-0.05%	0.22%
31	16	2.859	2.857	0.00	-0.08%	0.36%
Max		2.860	2.859	0.00	0.00%	0.91%
Average		2.860	2.858	0.00	-0.04%	0.21%
Min		2.859	2.855	0.00	-0.19%	0.02%
Std Dev		0.000	0.001	0.00	0.04%	0.20%

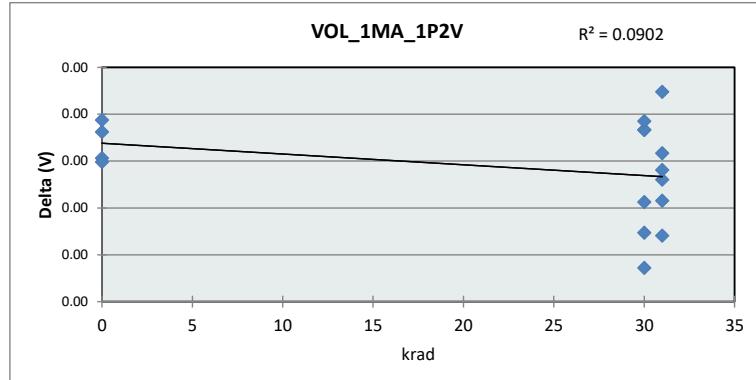


VOH_N5P5MA_3V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	3.1					
Min Limit	2.49					
krad	0	30	31			
LL	2.49	2.49	2.49			
Min	2.85	2.86	2.86			
Average	2.86	2.86	2.86			
Max	2.86	2.86	2.86			
UL	3.10	3.10	3.10			

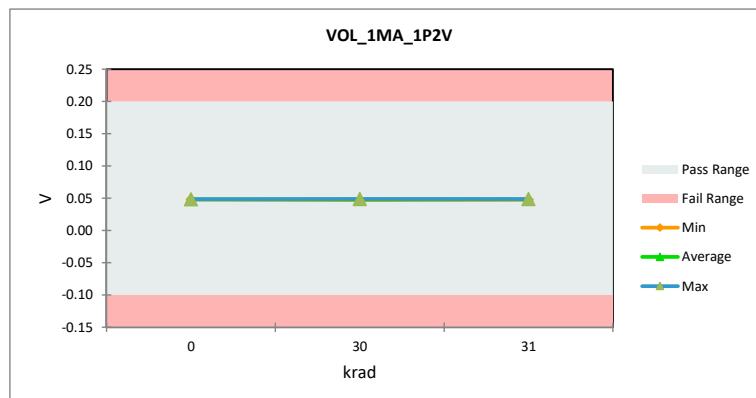


TID Report SN54SC3T97-SEP

VOL_1MA_1P2V						
	Test Site					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.048	0.048	0.00	0.91%	0.15%
0	2	0.048	0.048	0.00	0.07%	0.01%
0	3	0.048	0.048	0.00	0.65%	0.10%
0	4	0.048	0.048	0.00	-0.02%	0.00%
30	5	0.048	0.047	0.00	-2.36%	0.38%
30	6	0.049	0.048	0.00	-1.57%	0.25%
30	7	0.048	0.048	0.00	0.69%	0.11%
30	8	0.048	0.048	0.00	0.69%	0.11%
30	9	0.048	0.049	0.00	0.88%	0.14%
30	10	0.048	0.048	0.00	-0.91%	0.15%
31	11	0.048	0.048	0.00	-1.65%	0.27%
31	12	0.049	0.048	0.00	-0.87%	0.14%
31	13	0.048	0.049	0.00	1.54%	0.25%
31	14	0.048	0.048	0.00	0.17%	0.03%
31	15	0.048	0.048	0.00	-0.41%	0.07%
31	16	0.048	0.048	0.00	-0.20%	0.03%
Max		0.049	0.049	0.00	1.54%	0.38%
Average		0.048	0.048	0.00	-0.15%	0.14%
Min		0.048	0.047	0.00	-2.36%	0.00%
Std Dev		0.000	0.000	0.00	1.08%	0.11%



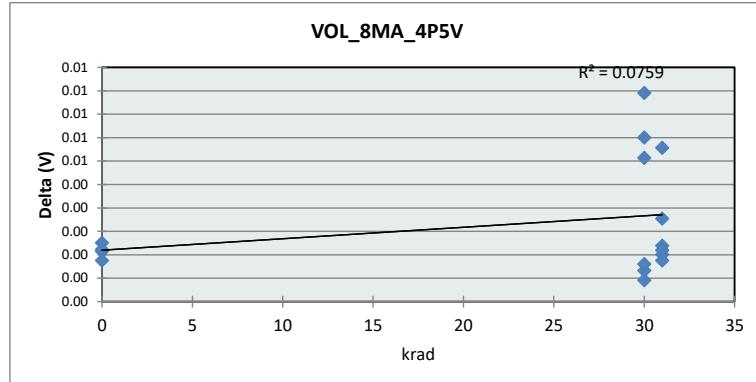
VOL_1MA_1P2V						
	Test Site					
krad	LL	Min	Average	Max	UL	
0	-0.10	-0.10	-0.10	0.05	0.05	0.05
30	-0.10	-0.10	-0.10	0.05	0.05	0.05
31	-0.10	-0.10	-0.10	0.05	0.05	0.05



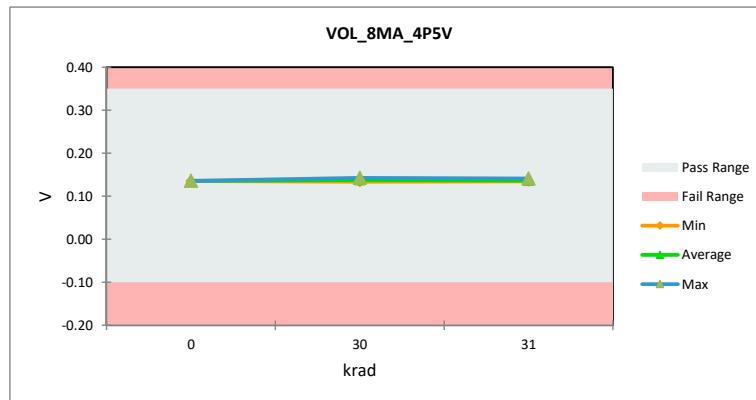
TID Report

SN54SC3T97-SEP

VOL_8MA_4P5V										
Test Site	CLAB	Tester	ETS88-01	Test Number	EQ774601	Units	V			
Max Limit	0.35	Min Limit	-0.1	krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.134	0.135	0.00	0.86%	0.26%				
0	2	0.134	0.136	0.00	1.13%	0.34%				
0	3	0.134	0.136	0.00	0.92%	0.27%				
0	4	0.135	0.135	0.00	0.57%	0.17%				
30	5	0.133	0.134	0.00	0.24%	0.07%				
30	6	0.134	0.134	0.00	-0.06%	0.02%				
30	7	0.136	0.141	0.01	3.79%	1.14%				
30	8	0.135	0.143	0.01	5.87%	1.76%				
30	9	0.135	0.141	0.01	4.46%	1.34%				
30	10	0.134	0.135	0.00	0.45%	0.13%				
31	11	0.133	0.135	0.00	1.04%	0.31%				
31	12	0.134	0.135	0.00	0.75%	0.22%				
31	13	0.136	0.141	0.01	4.11%	1.24%				
31	14	0.135	0.137	0.00	1.89%	0.56%				
31	15	0.135	0.135	0.00	0.57%	0.17%				
31	16	0.134	0.136	0.00	0.89%	0.27%				
Max		0.136	0.143	0.01	5.87%	1.76%				
Average		0.134	0.137	0.00	1.72%	0.52%				
Min		0.133	0.134	0.00	-0.06%	0.02%				
Std Dev		0.001	0.003	0.00	1.79%	0.54%				



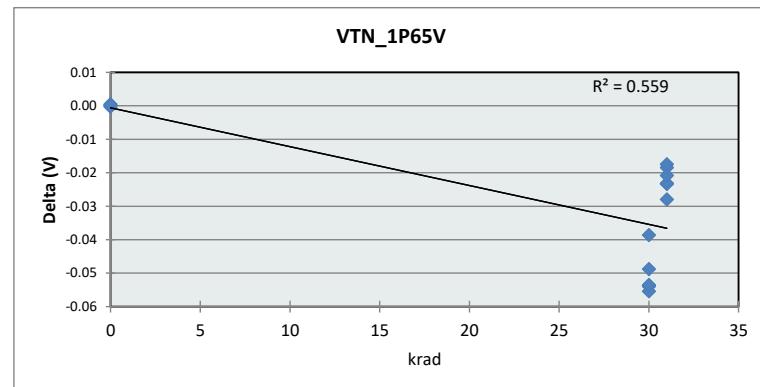
VOL_8MA_4P5V					
Test Site	CLAB	Tester	ETS88-01	Test Number	EQ774601
Max Limit	0.35	Min Limit	-0.1	krad	0 30 31
LL	-0.10	Min	-0.10	30	-0.10
Min	0.14	Average	0.13	31	0.13
Average	0.14	Max	0.14	0.14	0.14
Max	0.14	UL	0.14	31	0.35
UL	0.35		0.35		0.35



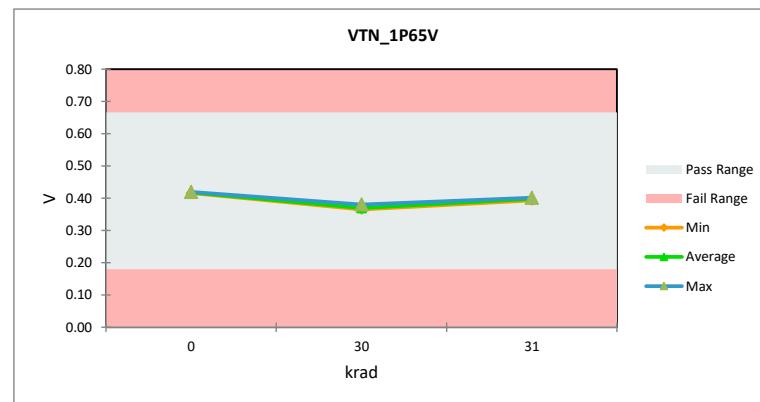
TID Report

SN54SC3T97-SEP

VTN_1P65V							
Test Site	CLAB	Tester	ETS88-01	Test Number	EQ774601	Units	V
Max Limit	0.666	Min Limit	0.18				
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range	
0	1	0.419	0.419	0.00	0.12%	0.10%	
0	2	0.418	0.418	0.00	0.06%	0.05%	
0	3	0.418	0.417	0.00	-0.05%	0.04%	
0	4	0.416	0.416	0.00	0.01%	0.01%	
30	5	0.420	0.372	-0.05	-11.59%	10.03%	
30	6	0.419	0.365	-0.05	-12.86%	11.09%	
30	7	0.421	0.367	-0.05	-12.78%	11.07%	
30	8	0.421	0.366	-0.06	-13.15%	11.40%	
30	9	0.420	0.367	-0.05	-12.73%	11.01%	
30	10	0.419	0.380	-0.04	-9.20%	7.93%	
31	11	0.420	0.397	-0.02	-5.56%	4.81%	
31	12	0.419	0.396	-0.02	-5.51%	4.75%	
31	13	0.421	0.400	-0.02	-4.93%	4.27%	
31	14	0.421	0.393	-0.03	-6.64%	5.75%	
31	15	0.420	0.402	-0.02	-4.39%	3.79%	
31	16	0.419	0.402	-0.02	-4.16%	3.59%	
Max		0.421	0.419	0.00	0.12%	11.40%	
Average		0.420	0.392	-0.03	-6.46%	5.61%	
Min		0.416	0.365	-0.05	-13.15%	0.01%	
Std Dev		0.001	0.020	0.02	5.04%	4.33%	



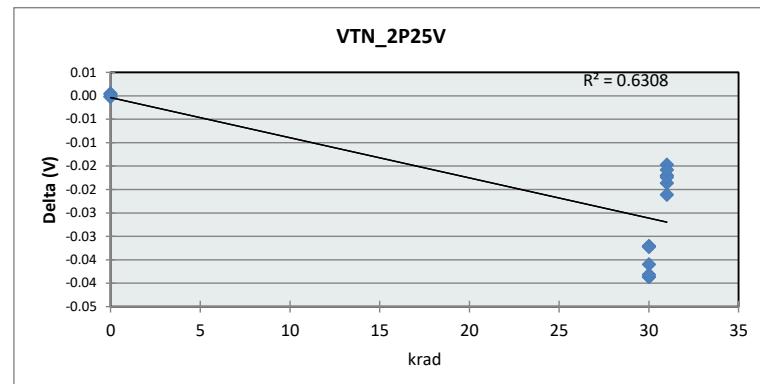
VTN_1P65V			
Test Site	CLAB	Tester	ETS88-01
Test Number	EQ774601	Units	V
Max Limit	0.666	Min Limit	0.18
krad	0	30	31
LL	0.18	0.18	0.18
Min	0.42	0.37	0.39
Average	0.42	0.37	0.40
Max	0.42	0.38	0.40
UL	0.67	0.67	0.67



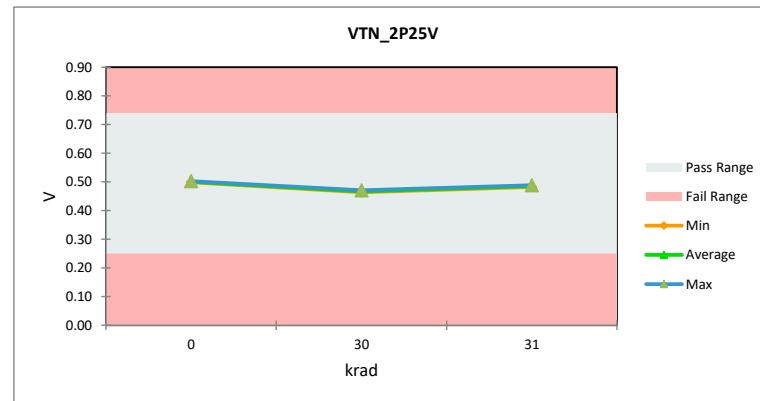
TID Report

SN54SC3T97-SEP

VTN_2P25V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.74					
Min Limit	0.25					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.502	0.502	0.00	0.10%	0.11%
0	2	0.501	0.501	0.00	0.05%	0.05%
0	3	0.500	0.500	0.00	-0.04%	0.04%
0	4	0.499	0.499	0.00	-0.03%	0.03%
30	5	0.503	0.467	-0.04	-7.16%	7.34%
30	6	0.502	0.464	-0.04	-7.70%	7.89%
30	7	0.503	0.465	-0.04	-7.68%	7.89%
30	8	0.503	0.465	-0.04	-7.58%	7.79%
30	9	0.503	0.471	-0.03	-6.38%	6.54%
30	10	0.501	0.469	-0.03	-6.44%	6.58%
31	11	0.503	0.486	-0.02	-3.38%	3.46%
31	12	0.502	0.484	-0.02	-3.70%	3.80%
31	13	0.503	0.486	-0.02	-3.45%	3.55%
31	14	0.503	0.482	-0.02	-4.20%	4.31%
31	15	0.503	0.488	-0.01	-2.92%	3.00%
31	16	0.501	0.485	-0.02	-3.16%	3.23%
Max		0.503	0.502	0.00	0.10%	7.89%
Average		0.502	0.482	-0.02	-3.98%	4.10%
Min		0.499	0.464	-0.04	-7.70%	0.03%
Std Dev		0.001	0.014	0.01	2.93%	2.98%



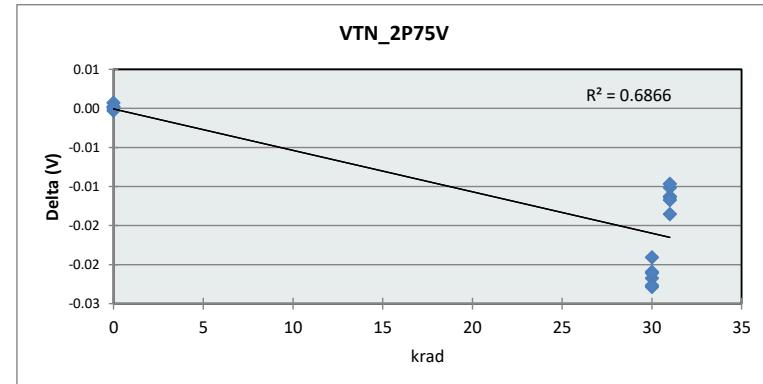
VTN_2P25V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.74					
Min Limit	0.25					
krad	0	30	31			
LL	0.25	0.25	0.25			
Min	0.50	0.46	0.48			
Average	0.50	0.47	0.49			
Max	0.50	0.47	0.49			
UL	0.74	0.74	0.74			



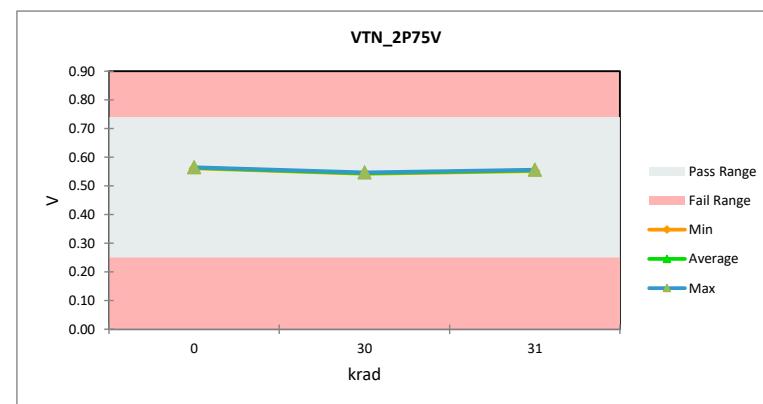
TID Report

SN54SC3T97-SEP

VTN_2P75V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.564	0.565	0.00	0.13%	0.15%
0	2	0.564	0.564	0.00	0.04%	0.05%
0	3	0.563	0.562	0.00	-0.05%	0.06%
0	4	0.561	0.561	0.00	0.01%	0.02%
30	5	0.566	0.545	-0.02	-3.72%	4.30%
30	6	0.565	0.543	-0.02	-3.85%	4.44%
30	7	0.566	0.543	-0.02	-4.04%	4.67%
30	8	0.566	0.543	-0.02	-4.00%	4.62%
30	9	0.566	0.547	-0.02	-3.37%	3.89%
30	10	0.563	0.542	-0.02	-3.72%	4.27%
31	11	0.566	0.555	-0.01	-1.99%	2.30%
31	12	0.565	0.554	-0.01	-1.80%	2.07%
31	13	0.566	0.555	-0.01	-2.01%	2.32%
31	14	0.566	0.553	-0.01	-2.39%	2.76%
31	15	0.566	0.556	-0.01	-1.70%	1.97%
31	16	0.563	0.551	-0.01	-2.08%	2.40%
Max		0.566	0.565	0.00	0.13%	4.67%
Average		0.565	0.553	-0.01	-2.16%	2.52%
Min		0.561	0.542	-0.02	-4.04%	0.02%
Std Dev		0.002	0.008	0.01	1.55%	1.74%



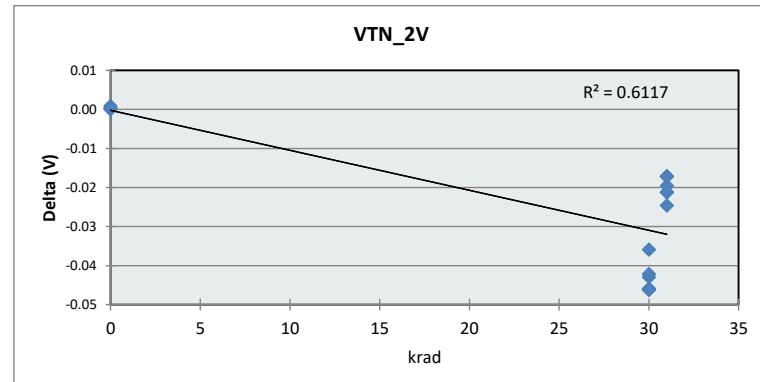
VTN_2P75V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
krad	0	30	31	LL	Min	Average
Max	0.566	0.25	0.25	0.25	0.25	0.25
Average	0.565	0.56	0.56	0.56	0.56	0.56
Min	0.561	0.54	0.54	0.54	0.54	0.54
Std Dev	0.002	0.74	0.74	0.74	0.74	0.74



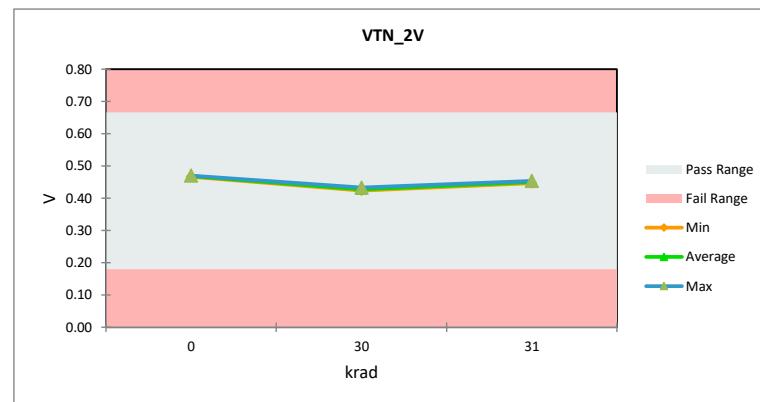
TID Report

SN54SC3T97-SEP

VTN_2V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
	CLAB			V		
	ETS88-01					
	EQ774601					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.469	0.470	0.00	0.19%	0.19%
0	2	0.469	0.469	0.00	0.05%	0.05%
0	3	0.468	0.468	0.00	0.00%	0.00%
0	4	0.466	0.466	0.00	0.06%	0.06%
30	5	0.471	0.428	-0.04	-9.12%	8.83%
30	6	0.469	0.424	-0.05	-9.77%	9.44%
30	7	0.471	0.425	-0.05	-9.80%	9.50%
30	8	0.471	0.425	-0.05	-9.80%	9.50%
30	9	0.471	0.429	-0.04	-8.95%	8.67%
30	10	0.469	0.433	-0.04	-7.66%	7.39%
31	11	0.471	0.450	-0.02	-4.50%	4.36%
31	12	0.469	0.448	-0.02	-4.52%	4.36%
31	13	0.471	0.452	-0.02	-4.15%	4.03%
31	14	0.471	0.447	-0.02	-5.22%	5.06%
31	15	0.471	0.454	-0.02	-3.63%	3.52%
31	16	0.469	0.452	-0.02	-3.67%	3.54%
Max		0.471	0.470	0.00	0.19%	9.50%
Average		0.470	0.446	-0.02	-5.03%	4.91%
Min		0.466	0.424	-0.04	-9.80%	0.00%
Std Dev		0.001	0.017	0.02	3.80%	3.62%



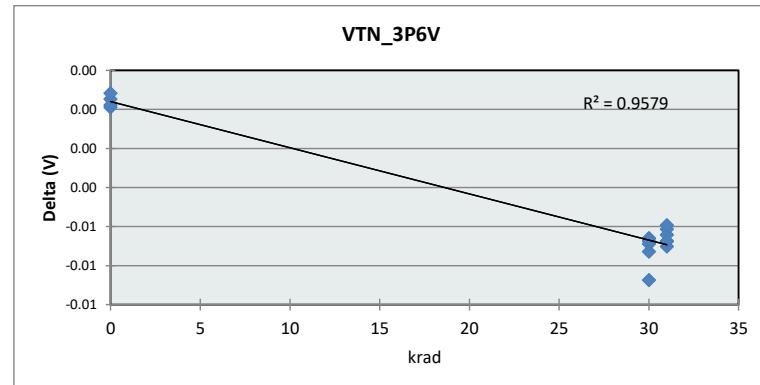
VTN_2V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
	CLAB			V		
	ETS88-01					
	EQ774601					
krad	0	30	31			
LL	0.18	0.18	0.18			
Min	0.47	0.42	0.45			
Average	0.47	0.43	0.45			
Max	0.47	0.43	0.45			
UL	0.67	0.67	0.67			



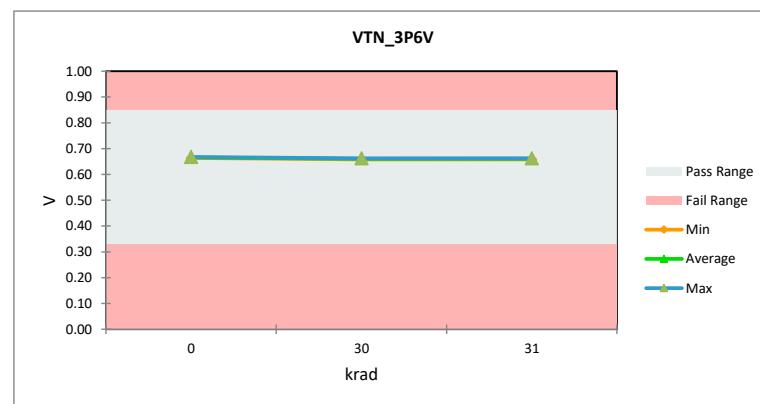
TID Report

SN54SC3T97-SEP

VTN_3P6V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.85					
Min Limit	0.33					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.667	0.667	0.00	0.08%	0.10%
0	2	0.666	0.667	0.00	0.12%	0.16%
0	3	0.665	0.665	0.00	0.02%	0.02%
0	4	0.663	0.664	0.00	0.03%	0.04%
30	5	0.669	0.662	-0.01	-0.99%	1.27%
30	6	0.667	0.658	-0.01	-1.31%	1.68%
30	7	0.669	0.662	-0.01	-0.99%	1.27%
30	8	0.668	0.661	-0.01	-1.09%	1.40%
30	9	0.668	0.661	-0.01	-1.03%	1.32%
30	10	0.665	0.658	-0.01	-1.01%	1.30%
31	11	0.669	0.662	-0.01	-1.01%	1.30%
31	12	0.667	0.661	-0.01	-0.96%	1.23%
31	13	0.669	0.662	-0.01	-0.92%	1.18%
31	14	0.668	0.662	-0.01	-0.89%	1.14%
31	15	0.668	0.661	-0.01	-1.05%	1.35%
31	16	0.665	0.658	-0.01	-1.01%	1.30%
Max		0.669	0.667	0.00	0.12%	1.68%
Average		0.667	0.662	-0.01	-0.75%	1.00%
Min		0.663	0.658	-0.01	-1.31%	0.02%
Std Dev		0.002	0.003	0.00	0.49%	0.56%



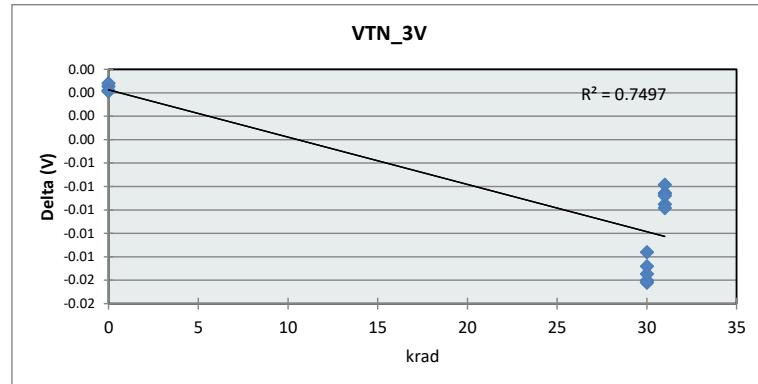
VTN_3P6V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.85					
Min Limit	0.33					
krad	0	30	31			
LL	0.33	0.33	0.33			
Min	0.66	0.66	0.66			
Average	0.67	0.66	0.66			
Max	0.67	0.66	0.66			
UL	0.85	0.85	0.85			



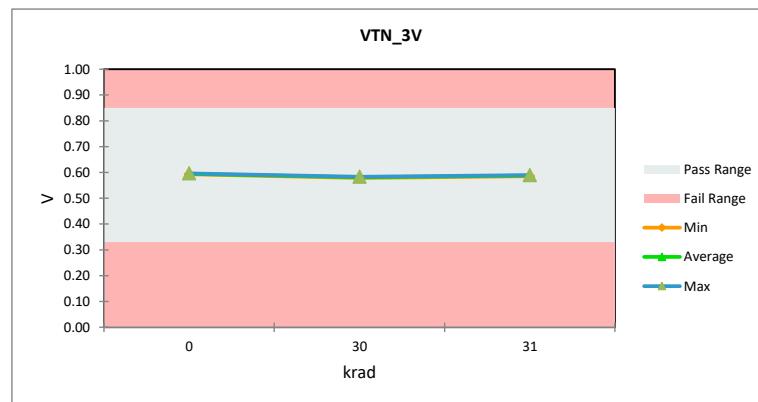
TID Report

SN54SC3T97-SEP

VTN_3V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.85					
Min Limit	0.33					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.596	0.596	0.00	0.09%	0.11%
0	2	0.594	0.595	0.00	0.14%	0.16%
0	3	0.593	0.594	0.00	0.03%	0.04%
0	4	0.593	0.593	0.00	0.02%	0.02%
30	5	0.597	0.582	-0.01	-2.48%	2.85%
30	6	0.597	0.581	-0.02	-2.71%	3.11%
30	7	0.597	0.581	-0.02	-2.71%	3.11%
30	8	0.597	0.581	-0.02	-2.69%	3.08%
30	9	0.597	0.583	-0.01	-2.28%	2.62%
30	10	0.594	0.578	-0.02	-2.60%	2.97%
31	11	0.597	0.587	-0.01	-1.59%	1.83%
31	12	0.597	0.588	-0.01	-1.43%	1.65%
31	13	0.597	0.589	-0.01	-1.32%	1.51%
31	14	0.597	0.587	-0.01	-1.65%	1.89%
31	15	0.597	0.588	-0.01	-1.44%	1.65%
31	16	0.594	0.585	-0.01	-1.48%	1.69%
Max		0.597	0.596	0.00	0.14%	3.11%
Average		0.596	0.587	-0.01	-1.51%	1.77%
Min		0.593	0.578	-0.01	-2.71%	0.02%
Std Dev		0.002	0.006	0.00	1.07%	1.16%



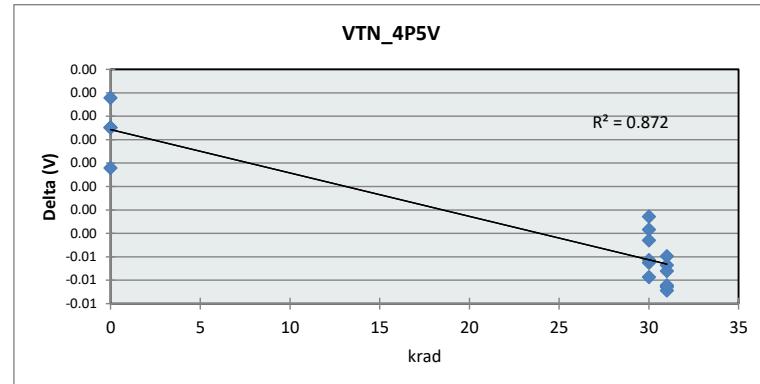
VTN_3V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	0.85					
Min Limit	0.33					
krad	0	30	31			
LL	0.33	0.33	0.33			
Min	0.59	0.58	0.59			
Average	0.59	0.58	0.59			
Max	0.60	0.58	0.59			
UL	0.85	0.85	0.85			



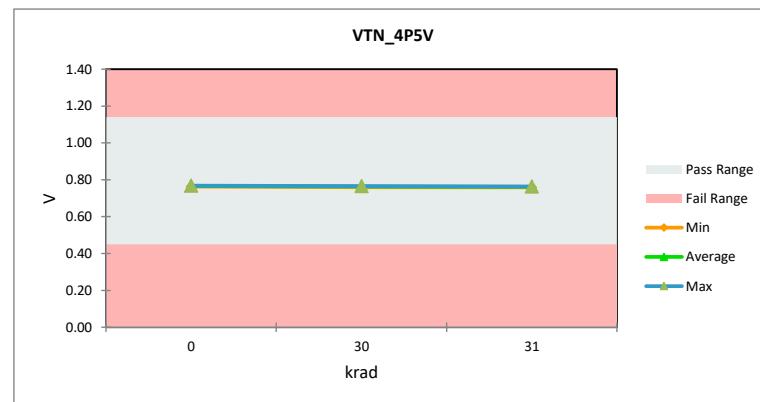
TID Report

SN54SC3T97-SEP

VTN_4P5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.14					
Min Limit	0.45					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.766	0.768	0.00	0.23%	0.26%
0	2	0.767	0.768	0.00	0.07%	0.08%
0	3	0.765	0.766	0.00	0.07%	0.07%
0	4	0.764	0.763	0.00	-0.16%	0.17%
30	5	0.770	0.765	-0.01	-0.68%	0.76%
30	6	0.767	0.763	0.00	-0.50%	0.56%
30	7	0.770	0.765	0.00	-0.56%	0.62%
30	8	0.768	0.764	0.00	-0.43%	0.48%
30	9	0.766	0.761	-0.01	-0.67%	0.74%
30	10	0.765	0.759	-0.01	-0.77%	0.85%
31	11	0.770	0.764	-0.01	-0.82%	0.91%
31	12	0.767	0.761	-0.01	-0.70%	0.78%
31	13	0.770	0.763	-0.01	-0.84%	0.93%
31	14	0.768	0.763	0.00	-0.65%	0.72%
31	15	0.766	0.761	-0.01	-0.73%	0.81%
31	16	0.765	0.759	-0.01	-0.81%	0.90%
Max		0.770	0.768	0.00	0.23%	0.93%
Average		0.767	0.763	0.00	-0.50%	0.60%
Min		0.764	0.759	-0.01	-0.84%	0.07%
Std Dev		0.002	0.003	0.00	0.35%	0.30%



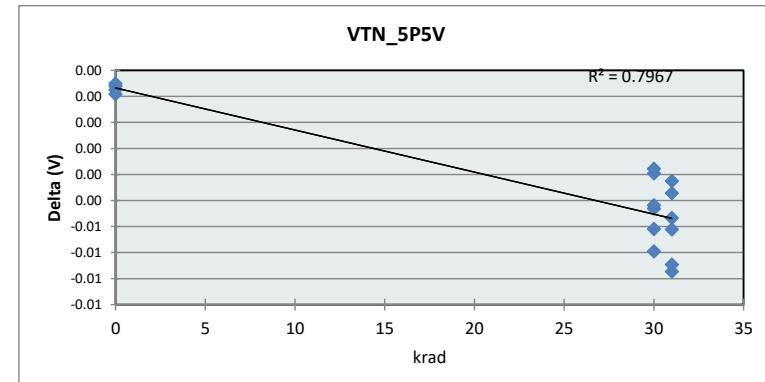
VTN_4P5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.14					
Min Limit	0.45					
LL	0	30	31			
Min	0.45	0.45	0.45			
Average	0.76	0.76	0.76			
Max	0.77	0.77	0.76			
UL	1.14	1.14	1.14			



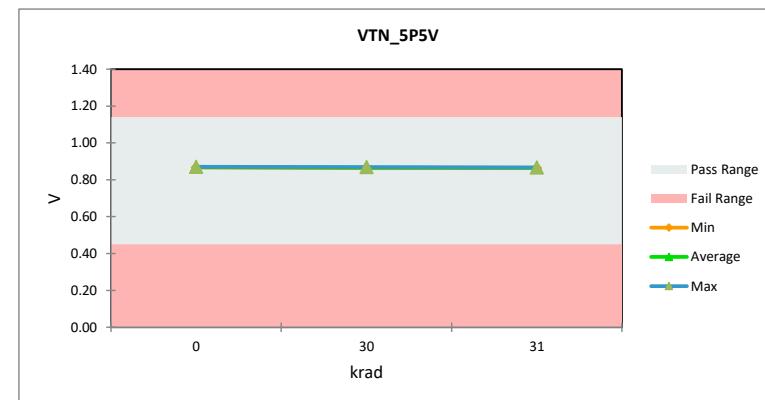
TID Report

SN54SC3T97-SEP

VTN_5P5V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
	CLAB			V		
Test Site	CLAB			V		
Tester		ETS88-01				
Test Number			EQ774601			
Units				V		
Max Limit				1.14		
Min Limit				0.45		
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.870	0.871	0.00	0.05%	0.06%
0	2	0.869	0.869	0.00	0.03%	0.04%
0	3	0.868	0.869	0.00	0.06%	0.07%
0	4	0.866	0.866	0.00	0.01%	0.01%
30	5	0.873	0.867	-0.01	-0.68%	0.86%
30	6	0.868	0.865	0.00	-0.34%	0.43%
30	7	0.872	0.869	0.00	-0.32%	0.40%
30	8	0.871	0.867	0.00	-0.49%	0.62%
30	9	0.870	0.865	-0.01	-0.58%	0.74%
30	10	0.868	0.863	0.00	-0.48%	0.61%
31	11	0.873	0.866	-0.01	-0.74%	0.94%
31	12	0.868	0.865	0.00	-0.37%	0.47%
31	13	0.872	0.867	0.00	-0.54%	0.68%
31	14	0.871	0.866	-0.01	-0.59%	0.74%
31	15	0.870	0.863	-0.01	-0.77%	0.97%
31	16	0.868	0.864	0.00	-0.43%	0.54%
Max		0.873	0.871	0.00	0.06%	0.97%
Average		0.870	0.866	0.00	-0.39%	0.51%
Min		0.866	0.863	0.00	-0.77%	0.01%
Std Dev		0.002	0.002	0.00	0.28%	0.32%



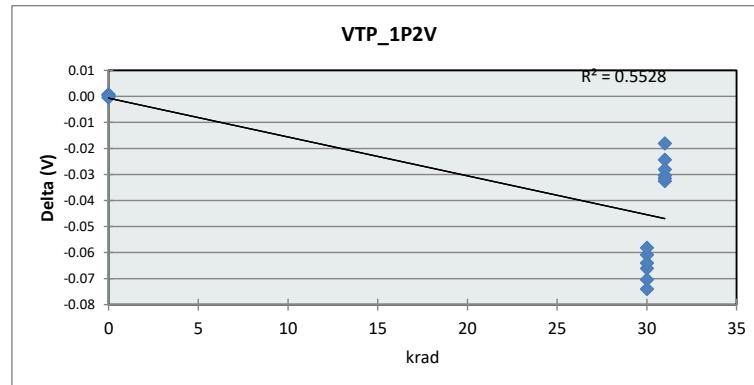
VTN_5P5V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
Test Site	CLAB			V		
Tester		ETS88-01				
Test Number			EQ774601			
Units				V		
Max Limit				1.14		
Min Limit				0.45		
krad	0	30	31			
LL	0.45	0.45	0.45			
Min	0.87	0.86	0.86			
Average	0.87	0.87	0.87			
Max	0.87	0.87	0.87			
UL	1.14	1.14	1.14			



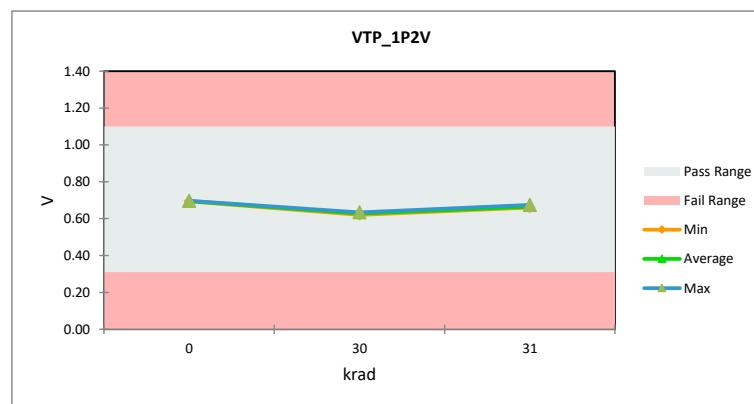
TID Report

SN54SC3T97-SEP

VTP_1P2V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.1					
Min Limit	0.31					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.696	0.697	0.00	0.12%	0.10%
0	2	0.696	0.696	0.00	0.08%	0.07%
0	3	0.694	0.694	0.00	0.04%	0.03%
0	4	0.694	0.694	0.00	-0.05%	0.05%
30	5	0.692	0.621	-0.07	-10.18%	8.91%
30	6	0.694	0.628	-0.07	-9.51%	8.36%
30	7	0.694	0.620	-0.07	-10.66%	9.37%
30	8	0.693	0.632	-0.06	-8.78%	7.70%
30	9	0.692	0.634	-0.06	-8.40%	7.36%
30	10	0.692	0.628	-0.06	-9.25%	8.11%
31	11	0.692	0.661	-0.03	-4.39%	3.85%
31	12	0.694	0.670	-0.02	-3.51%	3.08%
31	13	0.694	0.666	-0.03	-4.04%	3.55%
31	14	0.693	0.661	-0.03	-4.68%	4.11%
31	15	0.692	0.674	-0.02	-2.60%	2.28%
31	16	0.692	0.661	-0.03	-4.55%	3.98%
Max		0.696	0.697	0.00	0.12%	9.37%
Average		0.693	0.659	-0.03	-5.02%	4.43%
Min		0.692	0.620	-0.07	-10.66%	0.03%
Std Dev		0.001	0.028	0.03	3.95%	3.43%



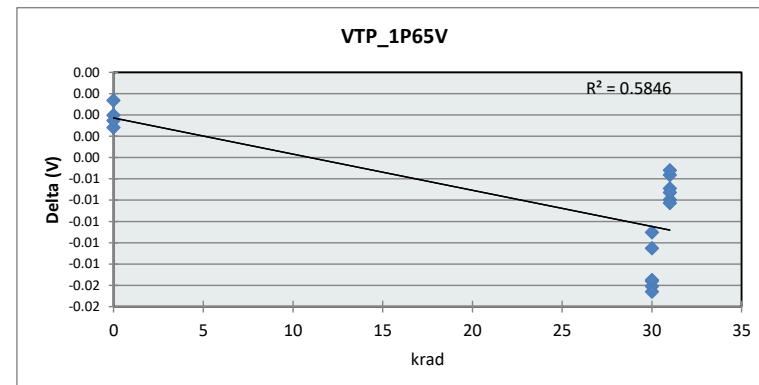
VTP_1P2V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.1					
Min Limit	0.31					
krad	0	30	31			
LL	0.31	0.31	0.31			
Min	0.69	0.62	0.66			
Average	0.70	0.63	0.67			
Max	0.70	0.63	0.67			
UL	1.10	1.10	1.10			



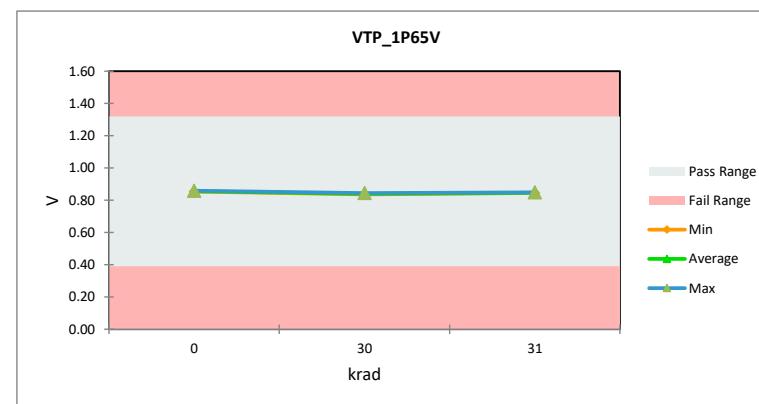
TID Report

SN54SC3T97-SEP

VTP_1P65V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.857	0.859	0.00	0.16%	0.15%
0	2	0.857	0.856	0.00	-0.14%	0.13%
0	3	0.853	0.853	0.00	0.00%	0.00%
0	4	0.855	0.854	0.00	-0.06%	0.06%
30	5	0.852	0.836	-0.02	-1.89%	1.73%
30	6	0.855	0.844	-0.01	-1.29%	1.18%
30	7	0.855	0.839	-0.02	-1.82%	1.68%
30	8	0.853	0.837	-0.02	-1.82%	1.67%
30	9	0.853	0.840	-0.01	-1.47%	1.35%
30	10	0.853	0.837	-0.02	-1.94%	1.78%
31	11	0.852	0.845	-0.01	-0.81%	0.74%
31	12	0.855	0.849	-0.01	-0.66%	0.61%
31	13	0.855	0.847	-0.01	-0.93%	0.85%
31	14	0.853	0.845	-0.01	-0.85%	0.78%
31	15	0.853	0.847	-0.01	-0.61%	0.56%
31	16	0.853	0.845	-0.01	-0.97%	0.89%
Max		0.857	0.859	0.00	0.16%	1.78%
Average		0.854	0.846	-0.01	-0.94%	0.88%
Min		0.852	0.836	-0.02	-1.94%	0.00%
Std Dev		0.002	0.007	0.01	0.71%	0.63%



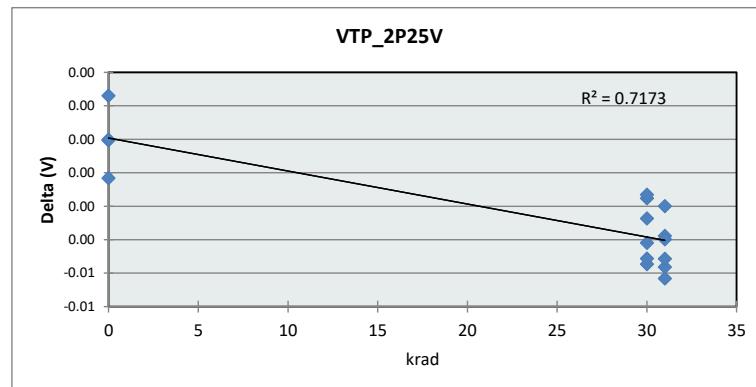
VTP_1P65V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
krad	0	30	31	LL	Min	Average
Max	0	30	31	0.39	0.39	0.39
Average	0.854	0.846	-0.01	0.85	0.84	0.85
Min	0.852	0.836	-0.02	0.86	0.84	0.85
UL	1.32	1.32	1.32	1.32	1.32	1.32



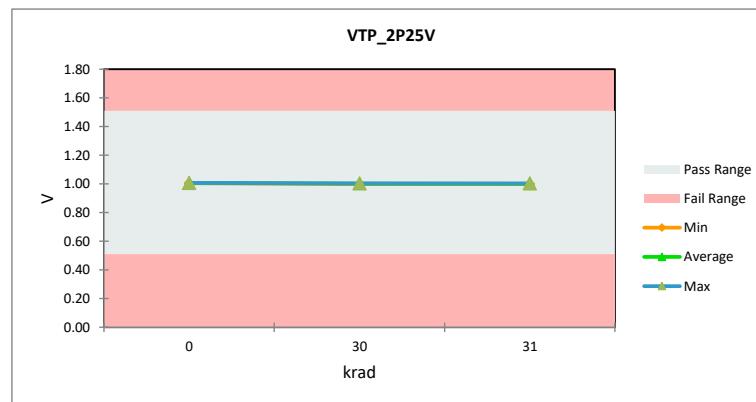
TID Report

SN54SC3T97-SEP

VTP_2P25V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.51					
Min Limit	0.51					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.008	1.007	0.00	-0.10%	0.10%
0	2	1.008	1.007	0.00	-0.10%	0.10%
0	3	1.005	1.006	0.00	0.03%	0.03%
0	4	1.007	1.004	0.00	-0.21%	0.22%
30	5	1.004	1.001	0.00	-0.28%	0.28%
30	6	1.006	1.003	0.00	-0.33%	0.34%
30	7	1.006	1.003	0.00	-0.26%	0.27%
30	8	1.004	0.999	0.00	-0.47%	0.47%
30	9	1.005	1.000	0.00	-0.45%	0.46%
30	10	1.005	1.000	0.00	-0.41%	0.41%
31	11	1.004	0.999	-0.01	-0.51%	0.52%
31	12	1.006	1.002	0.00	-0.39%	0.39%
31	13	1.006	1.003	0.00	-0.30%	0.30%
31	14	1.004	0.999	0.00	-0.48%	0.48%
31	15	1.005	1.000	0.00	-0.45%	0.46%
31	16	1.005	1.001	0.00	-0.40%	0.40%
Max		1.008	1.007	0.00	0.03%	0.52%
Average		1.005	1.002	0.00	-0.32%	0.33%
Min		1.004	0.999	0.00	-0.51%	0.03%
Std Dev		0.001	0.003	0.00	0.16%	0.15%



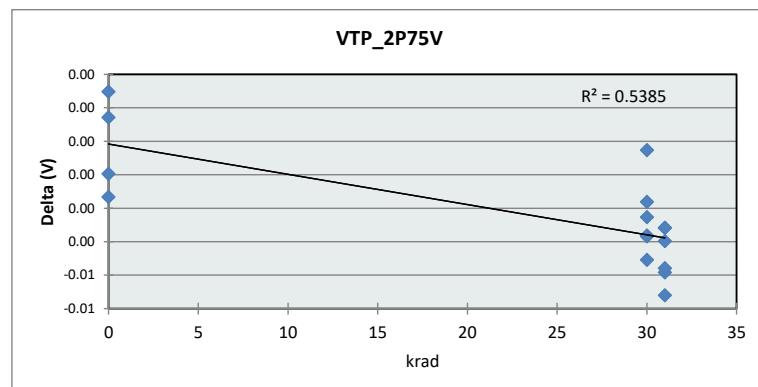
VTP_2P25V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.51					
Min Limit	0.51					
Max	0	30	31			
LL	0.51	0.51	0.51			
Min	1.00	1.00	1.00			
Average	1.01	1.00	1.00			
Max	1.01	1.00	1.00			
UL	1.51	1.51	1.51			



TID Report

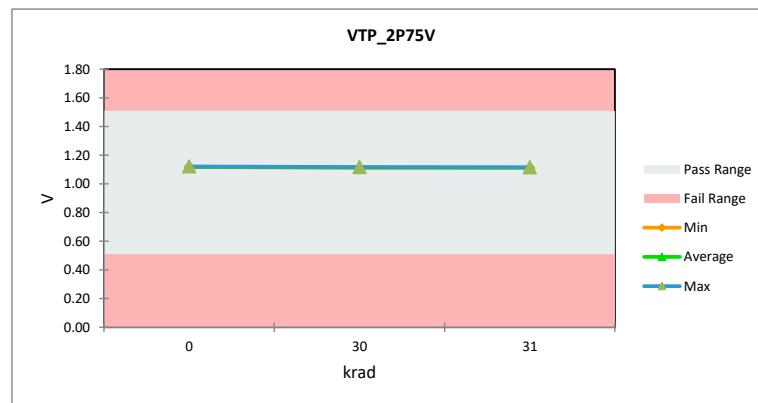
SN54SC3T97-SEP

VTP_2P75V						
Test Site		CLAB				
Tester		ETS88-01				
Test Number		EQ774601				
Units		V				
Max Limit		1.51				
Min Limit		0.51				
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.121	1.122	0.00	0.04%	0.05%
0	2	1.121	1.119	0.00	-0.18%	0.20%
0	3	1.120	1.119	0.00	-0.03%	0.03%
0	4	1.120	1.117	0.00	-0.24%	0.27%
30	5	1.118	1.115	0.00	-0.29%	0.33%
30	6	1.119	1.116	0.00	-0.25%	0.28%
30	7	1.119	1.117	0.00	-0.11%	0.13%
30	8	1.117	1.113	0.00	-0.41%	0.45%
30	9	1.118	1.114	0.00	-0.34%	0.38%
30	10	1.119	1.115	0.00	-0.34%	0.38%
31	11	1.118	1.113	-0.01	-0.50%	0.56%
31	12	1.119	1.115	0.00	-0.32%	0.36%
31	13	1.119	1.115	0.00	-0.32%	0.36%
31	14	1.117	1.112	0.00	-0.44%	0.49%
31	15	1.118	1.114	0.00	-0.36%	0.40%
31	16	1.119	1.114	0.00	-0.43%	0.48%
Max		1.121	1.122	0.00	0.04%	0.56%
Average		1.119	1.116	0.00	-0.28%	0.32%
Min		1.117	1.112	0.00	-0.50%	0.03%
Std Dev		0.001	0.003	0.00	0.15%	0.16%



VTP_2P75V

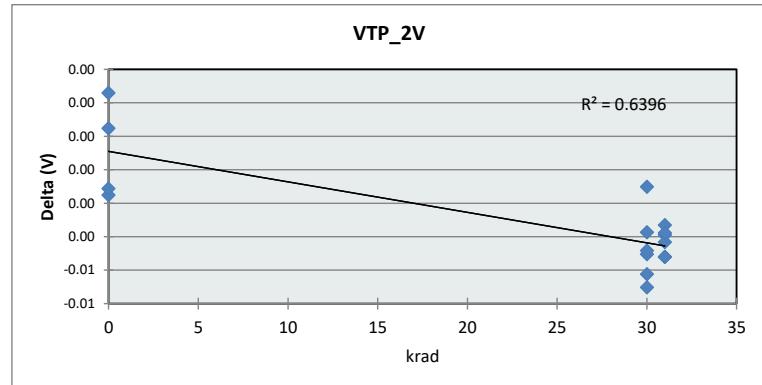
Test Site		CLAB		
Tester		ETS88-01		
Test Number		EQ774601		
Units		V		
Max Limit		1.51		
Min Limit		0.51		
krad	0	30	31	
LL	0.51	0.51	0.51	
Min	1.12	1.11	1.11	
Average	1.12	1.11	1.11	
Max	1.12	1.12	1.12	
UL	1.51	1.51	1.51	



TID Report

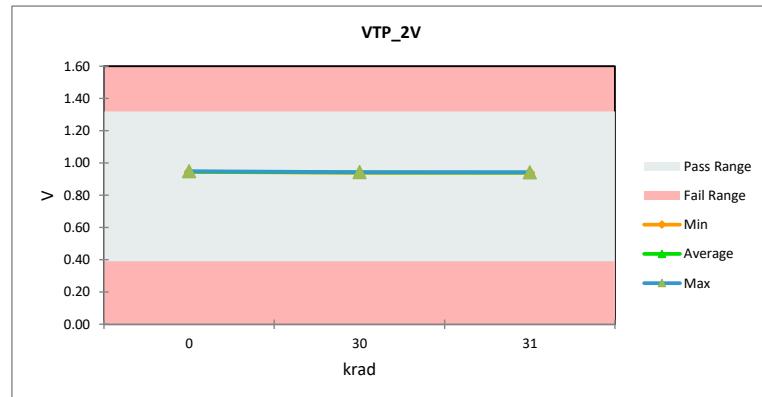
SN54SC3T97-SEP

VTP_2V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	1.32					
Min Limit	0.39					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	0.948	0.949	0.00	0.03%	0.03%
0	2	0.948	0.946	0.00	-0.29%	0.30%
0	3	0.946	0.945	0.00	-0.08%	0.08%
0	4	0.947	0.945	0.00	-0.27%	0.28%
30	5	0.944	0.941	0.00	-0.27%	0.27%
30	6	0.947	0.943	0.00	-0.41%	0.42%
30	7	0.946	0.942	0.00	-0.48%	0.49%
30	8	0.944	0.939	-0.01	-0.54%	0.55%
30	9	0.945	0.941	0.00	-0.47%	0.47%
30	10	0.945	0.940	-0.01	-0.58%	0.59%
31	11	0.944	0.940	0.00	-0.42%	0.42%
31	12	0.947	0.942	0.00	-0.44%	0.45%
31	13	0.946	0.942	0.00	-0.39%	0.39%
31	14	0.944	0.940	0.00	-0.49%	0.50%
31	15	0.945	0.941	0.00	-0.49%	0.50%
31	16	0.945	0.941	0.00	-0.41%	0.42%
Max		0.948	0.949	0.00	0.03%	0.59%
Average		0.946	0.942	0.00	-0.37%	0.38%
Min		0.944	0.939	0.00	-0.58%	0.03%
Std Dev		0.001	0.003	0.00	0.16%	0.16%



VTP_2V

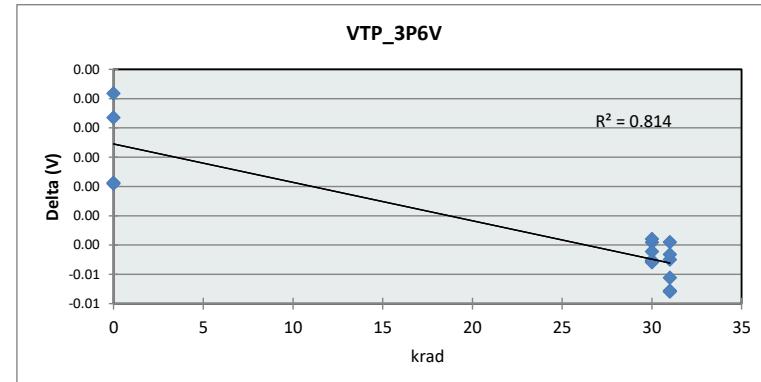
Test Site	CLAB		
Tester	ETS88-01		
Test Number	EQ774601		
Units	V		
Max Limit	1.32		
Min Limit	0.39		
krad	0	30	31
LL	0.39	0.39	0.39
Min	0.94	0.94	0.94
Average	0.95	0.94	0.94
Max	0.95	0.94	0.94
UL	1.32	1.32	1.32



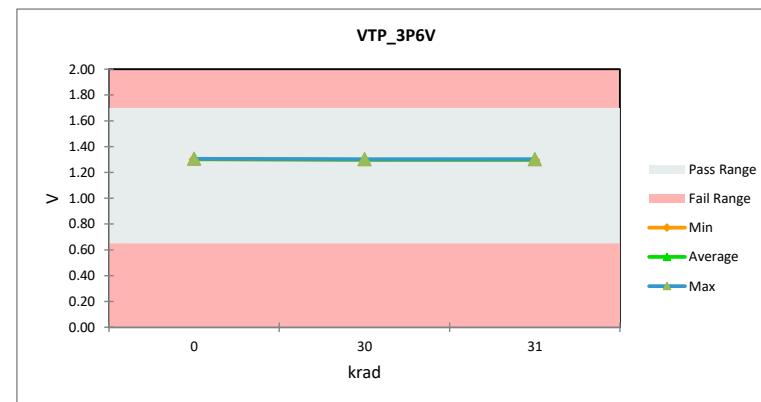
TID Report

SN54SC3T97-SEP

VTP_3P6V							
Test Site	CLAB	Tester	ETS88-01	Test Number	EQ774601	Units	V
Max Limit	1.7	Min Limit	0.65				
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range	
0	1	1.305	1.306	0.00	0.03%	0.03%	
0	2	1.303	1.301	0.00	-0.14%	0.18%	
0	3	1.304	1.306	0.00	0.09%	0.11%	
0	4	1.303	1.301	0.00	-0.15%	0.18%	
30	5	1.303	1.299	0.00	-0.35%	0.43%	
30	6	1.304	1.299	0.00	-0.35%	0.43%	
30	7	1.306	1.302	0.00	-0.30%	0.37%	
30	8	1.302	1.298	0.00	-0.29%	0.36%	
30	9	1.303	1.299	0.00	-0.35%	0.44%	
30	10	1.303	1.299	0.00	-0.32%	0.40%	
31	11	1.303	1.298	-0.01	-0.43%	0.53%	
31	12	1.304	1.299	0.00	-0.34%	0.43%	
31	13	1.306	1.302	0.00	-0.30%	0.37%	
31	14	1.302	1.296	-0.01	-0.43%	0.53%	
31	15	1.303	1.298	-0.01	-0.39%	0.49%	
31	16	1.303	1.299	0.00	-0.33%	0.41%	
Max		1.306	1.306	0.00	0.09%	0.53%	
Average		1.304	1.300	0.00	-0.27%	0.36%	
Min		1.302	1.296	-0.01	-0.43%	0.03%	
Std Dev		0.001	0.003	0.00	0.15%	0.15%	



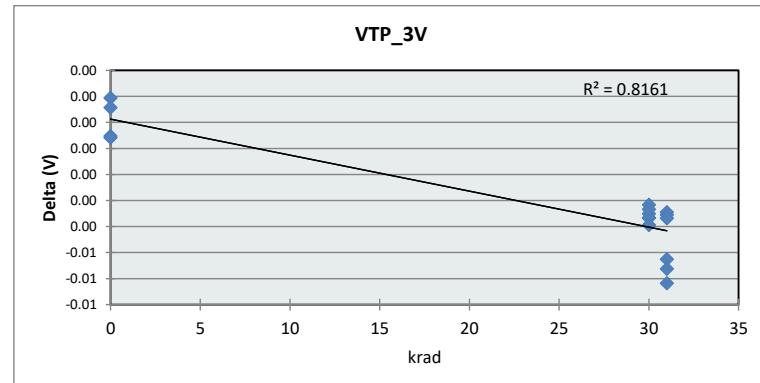
VTP_3P6V							
Test Site	CLAB	Tester	ETS88-01	Test Number	EQ774601	Units	V
Max Limit	1.7	Min Limit	0.65				
krad	0	30	31				
LL	0.65	0.65	0.65				
Min	1.30	1.30	1.30				
Average	1.30	1.30	1.30				
Max	1.31	1.30	1.30				
UL	1.70	1.70	1.70				



TID Report

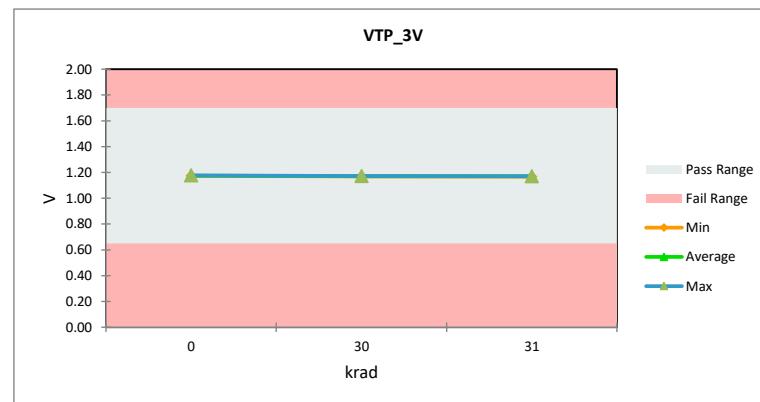
SN54SC3T97-SEP

VTP_3V						
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.176	1.177	0.00	0.08%	0.09%
0	2	1.176	1.175	0.00	-0.04%	0.05%
0	3	1.175	1.174	0.00	-0.05%	0.06%
0	4	1.173	1.173	0.00	0.05%	0.05%
30	5	1.174	1.170	0.00	-0.30%	0.33%
30	6	1.174	1.171	0.00	-0.27%	0.30%
30	7	1.176	1.172	0.00	-0.31%	0.35%
30	8	1.173	1.169	0.00	-0.31%	0.35%
30	9	1.173	1.170	0.00	-0.28%	0.32%
30	10	1.175	1.171	0.00	-0.34%	0.38%
31	11	1.174	1.169	-0.01	-0.45%	0.50%
31	12	1.174	1.171	0.00	-0.30%	0.34%
31	13	1.176	1.170	-0.01	-0.53%	0.59%
31	14	1.173	1.167	-0.01	-0.48%	0.54%
31	15	1.173	1.170	0.00	-0.29%	0.33%
31	16	1.175	1.171	0.00	-0.31%	0.35%
Max		1.176	1.177	0.00	0.08%	0.59%
Average		1.174	1.171	0.00	-0.26%	0.31%
Min		1.173	1.167	-0.01	-0.53%	0.05%
Std Dev		0.001	0.003	0.00	0.18%	0.17%



VTP_3V

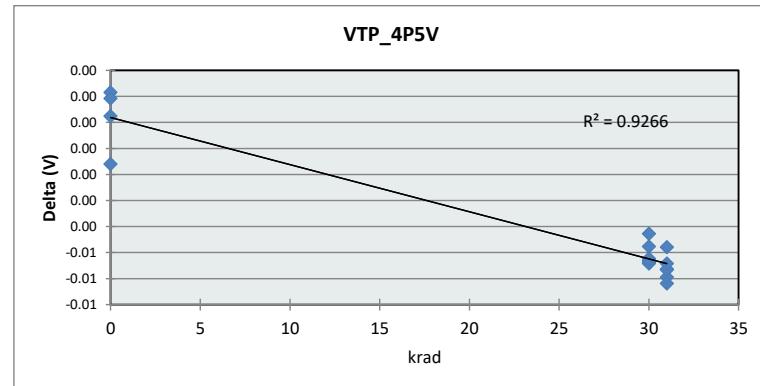
	Test Site	Tester	Test Number	Units	Max Limit	Min Limit
krad	0	30	31			
LL	0.65	0.65	0.65			
Min	1.17	1.17	1.17			
Average	1.17	1.17	1.17			
Max	1.18	1.17	1.17			
UL	1.70	1.70	1.70			



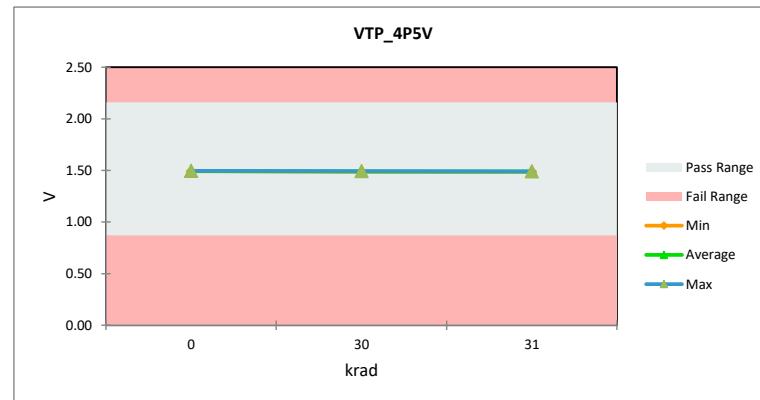
TID Report

SN54SC3T97-SEP

VTP_4P5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	2.16					
Min Limit	0.87					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.495	1.496	0.00	0.08%	0.09%
0	2	1.491	1.492	0.00	0.06%	0.07%
0	3	1.494	1.494	0.00	0.02%	0.02%
0	4	1.494	1.493	0.00	-0.11%	0.12%
30	5	1.494	1.488	-0.01	-0.36%	0.42%
30	6	1.494	1.489	-0.01	-0.35%	0.41%
30	7	1.497	1.492	0.00	-0.29%	0.33%
30	8	1.492	1.487	0.00	-0.32%	0.37%
30	9	1.494	1.488	-0.01	-0.36%	0.42%
30	10	1.493	1.488	-0.01	-0.35%	0.41%
31	11	1.494	1.488	-0.01	-0.38%	0.44%
31	12	1.494	1.489	0.00	-0.32%	0.37%
31	13	1.497	1.491	-0.01	-0.40%	0.46%
31	14	1.492	1.487	-0.01	-0.38%	0.44%
31	15	1.494	1.488	-0.01	-0.36%	0.42%
31	16	1.493	1.487	-0.01	-0.41%	0.48%
Max		1.497	1.496	0.00	0.08%	0.48%
Average		1.494	1.490	0.00	-0.26%	0.33%
Min		1.491	1.487	0.00	-0.41%	0.02%
Std Dev		0.001	0.003	0.00	0.17%	0.16%



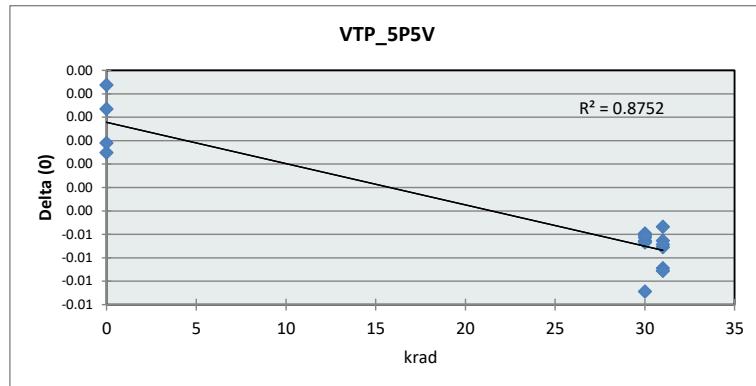
VTP_4P5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	V					
Max Limit	2.16					
Min Limit	0.87					
krad	0	30	31			
LL	0.87	0.87	0.87			
Min	1.49	1.49	1.49			
Average	1.49	1.49	1.49			
Max	1.50	1.49	1.49			
UL	2.16	2.16	2.16			



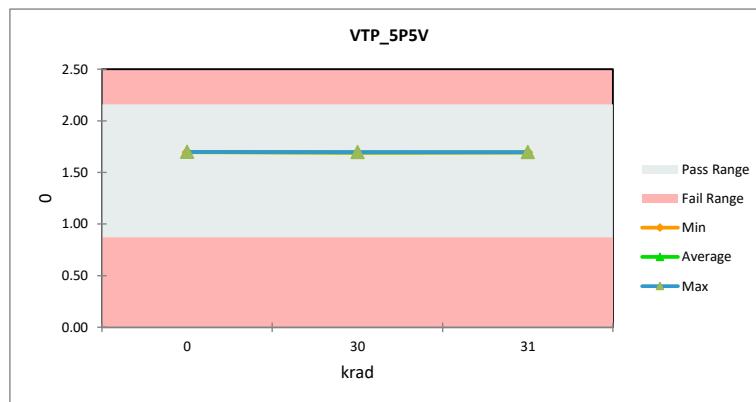
TID Report

SN54SC3T97-SEP

VTP_5P5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	0					
Max Limit	2.16					
Min Limit	0.87					
krad	Serial #	PreTestHDR	PostTestHDR	Delta	Delta %	% of Limit Range
0	1	1.700	1.698	0.00	-0.09%	0.12%
0	2	1.694	1.696	0.00	0.08%	0.11%
0	3	1.700	1.699	0.00	-0.06%	0.08%
0	4	1.697	1.697	0.00	0.02%	0.03%
30	5	1.699	1.694	-0.01	-0.31%	0.41%
30	6	1.699	1.694	0.00	-0.29%	0.38%
30	7	1.703	1.698	-0.01	-0.31%	0.41%
30	8	1.698	1.693	-0.01	-0.30%	0.40%
30	9	1.699	1.694	-0.01	-0.30%	0.39%
30	10	1.698	1.690	-0.01	-0.44%	0.58%
31	11	1.699	1.693	-0.01	-0.38%	0.50%
31	12	1.699	1.694	0.00	-0.28%	0.36%
31	13	1.703	1.696	-0.01	-0.39%	0.51%
31	14	1.698	1.692	-0.01	-0.33%	0.43%
31	15	1.699	1.694	-0.01	-0.31%	0.41%
31	16	1.698	1.692	-0.01	-0.32%	0.42%
Max		1.703	1.699	0.00	0.08%	0.58%
Average		1.699	1.695	0.00	-0.25%	0.35%
Min		1.694	1.690	0.00	-0.44%	0.03%
Std Dev		0.002	0.003	0.00	0.15%	0.17%



VTP_5P5V						
Test Site	CLAB					
Tester	ETS88-01					
Test Number	EQ774601					
Units	0					
Max Limit	2.16					
Min Limit	0.87					
krad	0	30	31			
LL	0.87	0.87	0.87			
Min	1.70	1.69	1.69			
Average	1.70	1.69	1.69			
Max	1.70	1.70	1.70			
UL	2.16	2.16	2.16			



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